

# SiPM Test Facilities at BNL

*Thomas Tsang*  
Instrumentation Division

**DUNE FD3 Mini-Workshop Toward a Combined Photon Detection and Field Cage System**

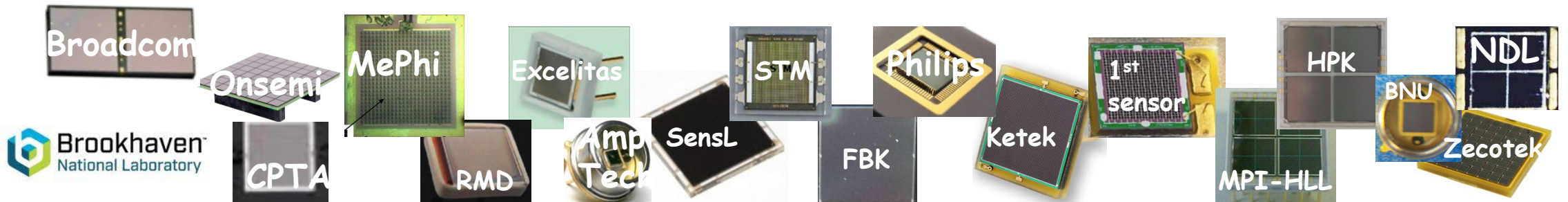
*June 26-28, 2023*

*Stony Brook University Physics Building*

# Outline:

- Types of SiPM tested, SiPM measurement setup
- Recap of DUNE SiPMs
- Challenge and solution on large SiPM capacitance
- nEXO SiPMs selection status: HPK & FBK
- Light readout concept using LArASIC Cold Electronics – IEEE 2021
  - Photoelectron spectroscopy: response to single and multiple photoelectron
  - Charge calibration, SiPM avalanche gain, S/N ratio
  - Timing and coincidence resolution
  - Time coincidence detection of Dark Pulses
- SiPM terminal capacitance measurements

# SiPM R&D and production around the globe



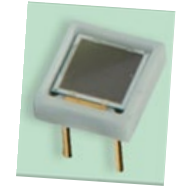
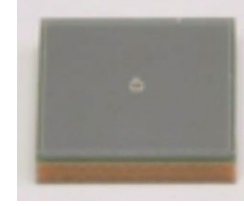
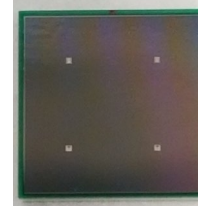
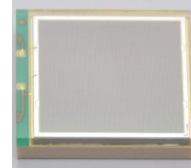
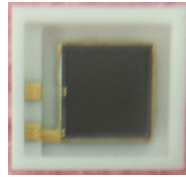
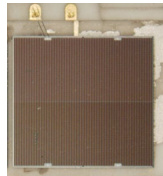
# *SiPM tested from various vendors*

**FBK**

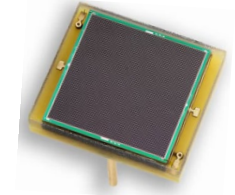
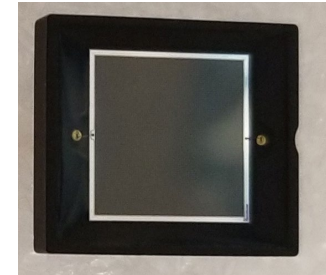
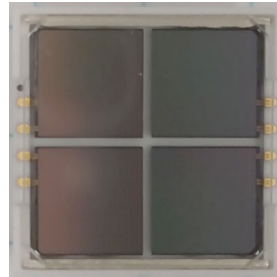
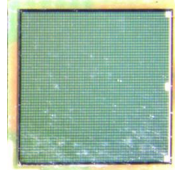
**HPK**

**others**

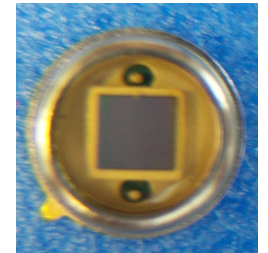
3x3 mm<sup>2</sup>



6x6 mm<sup>2</sup>



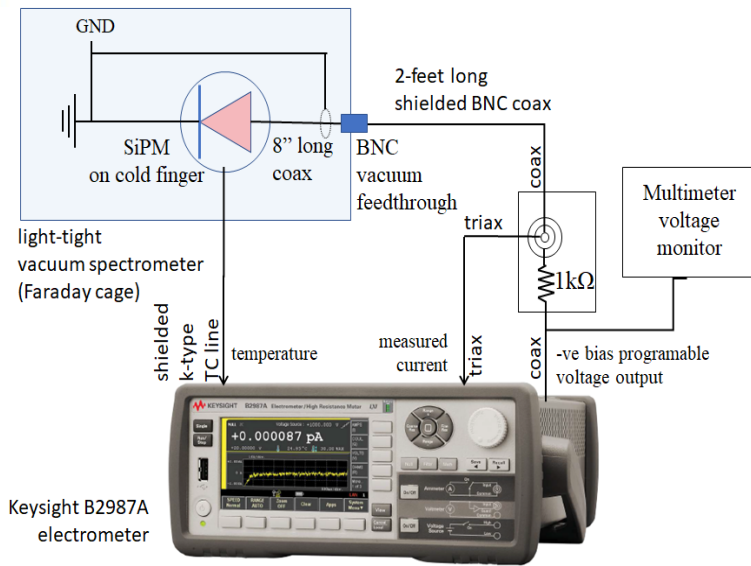
10x10 mm<sup>2</sup>



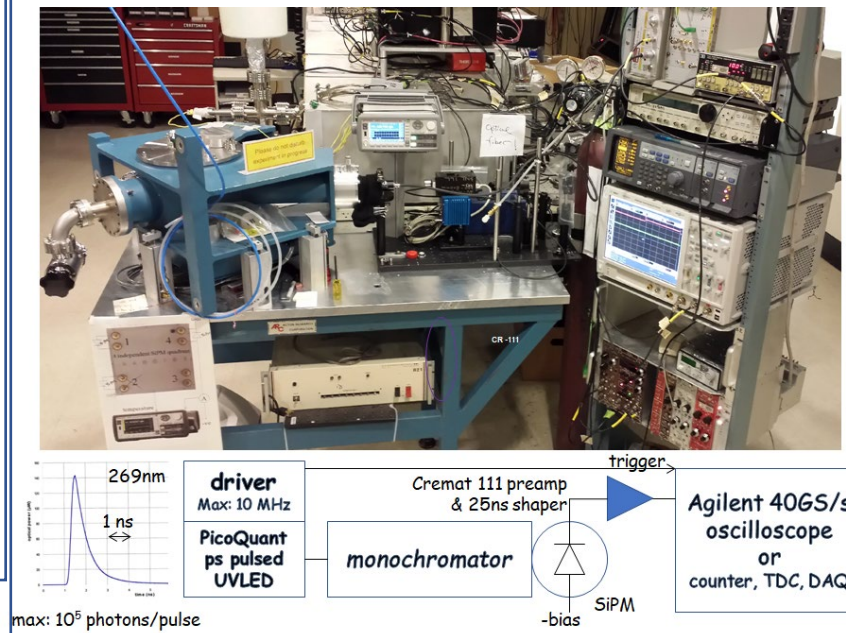
*The Instrumentation Division at BNL has been testing SiPMs from various vendors for difference science programs in the past 8 years; primary targeted to operate SiPMs in cryogenic temperature and in noble liquids.*

- Packaging and bond bare SiPM chips to various carriers
- Current-voltage (IV) characterization: at room temperature, 165K, 85K in vacuum, LN<sub>2</sub>, and in purified LAr, LXe, and LKr
- Charge gain,  $\mu$ cell and terminal capacitance, quench resistance,  $V_{\text{breakdown}}$ ,  $I_{\text{dark}}$
- time correlated and time uncorrelated avalanche noise measurements: optical cross-talk (CT), after-pulse (AP), and thermally activated dark count (DCR), respectively.
- photodetection efficiency (PDE) from VUV to NIR wavelength range and photon number resolving (PNR) capability.

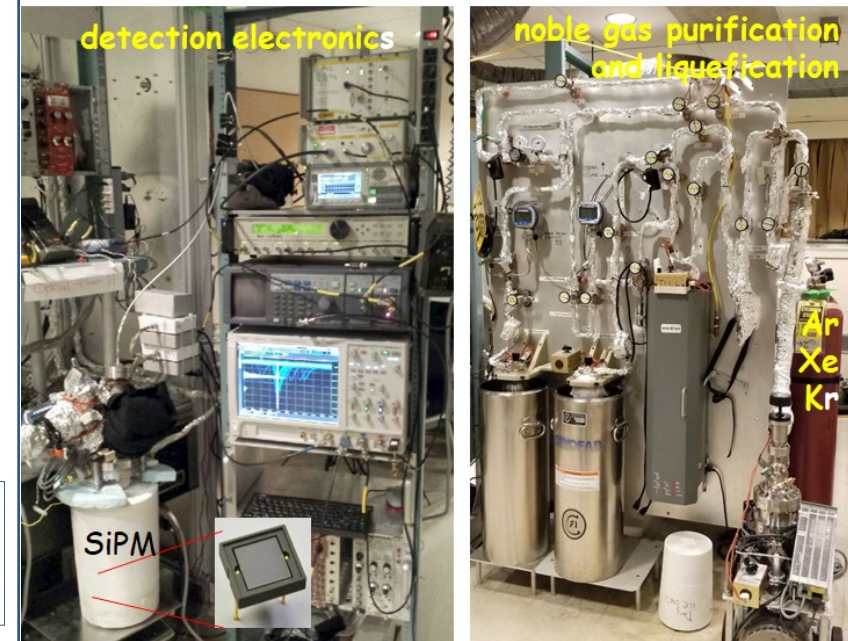
IV measurement



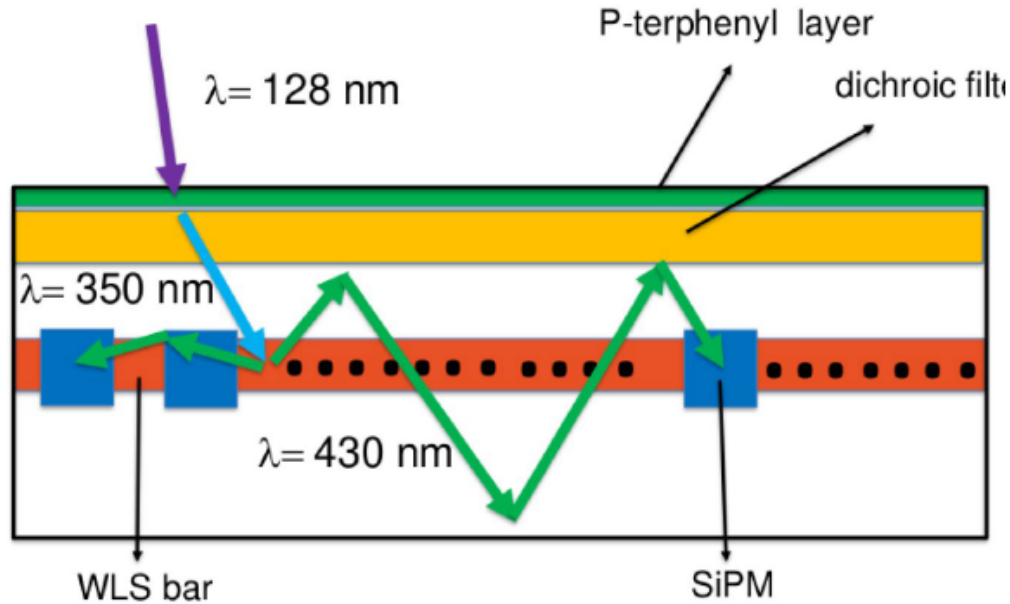
charge gain, noise, and PDE measurement



SiPM test in purified noble Liquid

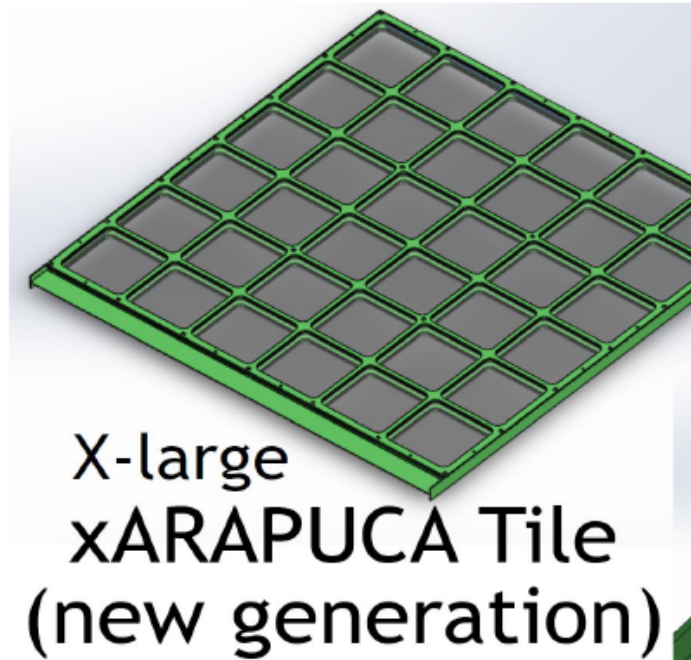


# DUNE FD-2: ARAPUCA (Argon R&D Advanced Program at UniCamp).



Credits: F. Terranova

- 160 SiPMs (40 per side)
  - Glued to WLS Bar for improved optical contact
- SiPMs mounted on Kapton flexi-PCB

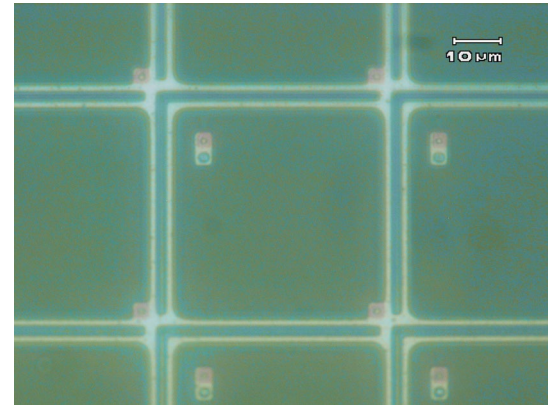
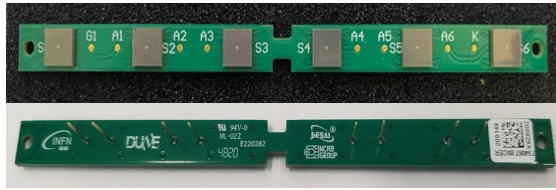


*Readout a challenge for DUNE and SBND!*

- Optical area
  - 600 mm x 600 mm = 3600 cm<sup>2</sup>
- SiPM area
  - 160 x 0.36 cm<sup>2</sup> ≈ 60 cm<sup>2</sup>
  - ≈ 1.7 % of opt. area
- SiPM array capacitance
  - ≈ 200 nF for  $V_{bd} \sim 45$  V;
  - ≈ 260 nF for  $V_{bd} \sim 37$  V

M.C. Queiroga Bazetto, V.L. Pimentel, A.A. Machado and E. Segreto, in Campinas, Brazil

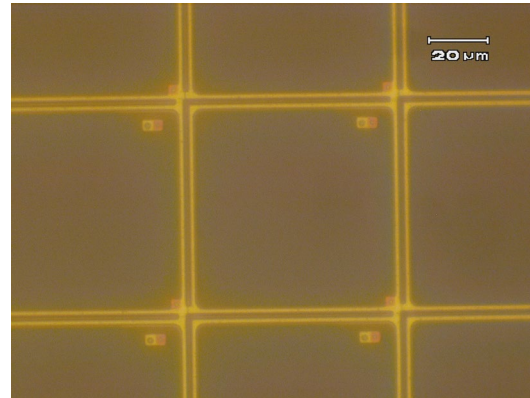
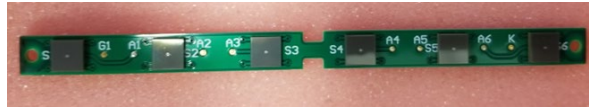
**DUNE S13360-6050-HS-HRQ**  
high  $R_q$ , normal  $V_{bd}$



**S13360-6050-HS-HRQ spec.**

area	6x6 mm <sup>2</sup>
pixel size	50 μm
# of pixels	14331
$V_{bd}$ (RT, LN2)	53 V, 42 V
Capacitance	1.28 nF

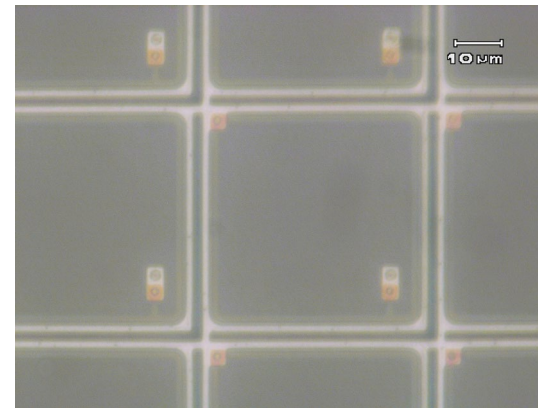
**DUNE S13360-6075-HS-HRQ**  
high  $R_q$ , normal  $V_{bd}$



**S13360-6075-HS-HRQ**

area	6x6 mm <sup>2</sup>
pixel size	75 μm
# of pixels	6364
$V_{bd}$ (RT, LN2)	51 V, 41 V
Capacitance	1.9 nF

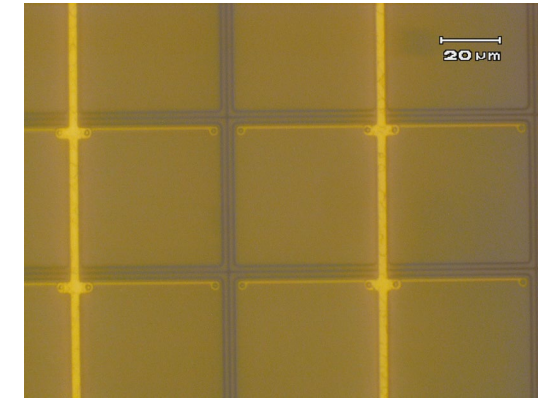
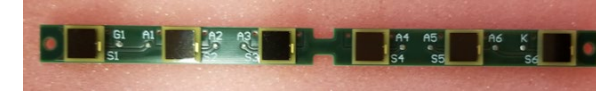
**ProtoDUNE FNAL**  
S14160-6050-HS low  $V_{bd}$



**S14160-6050-HS**

area	6x6 mm <sup>2</sup>
pixel size	50 μm
# of pixels	14331
$V_{bd}$ (RT, LN2)	38 V, 32 V
Capacitance	~2.3 nF

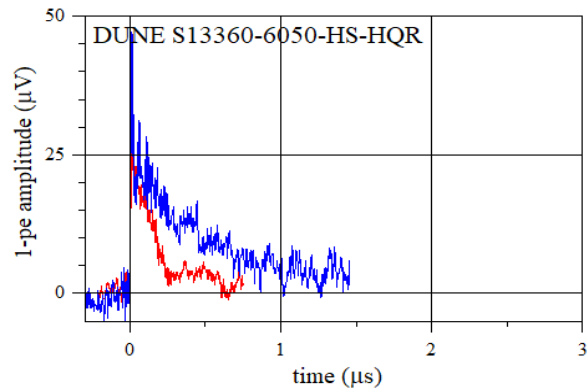
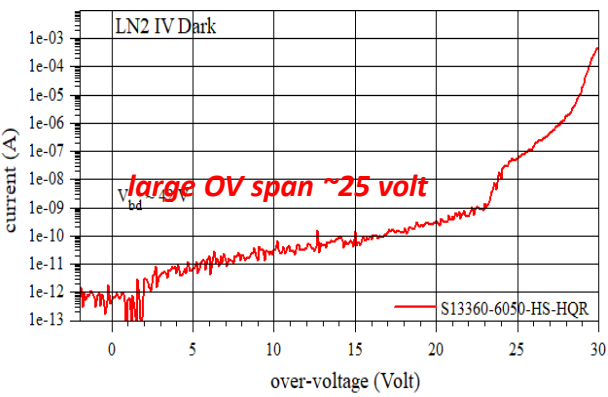
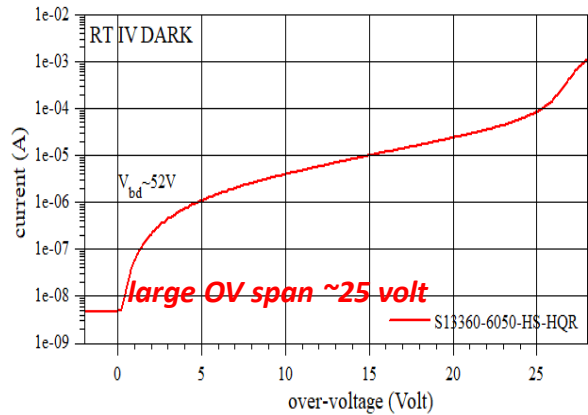
**DUNE FBK triple-trench 50μm**  
low  $V_{bd}$



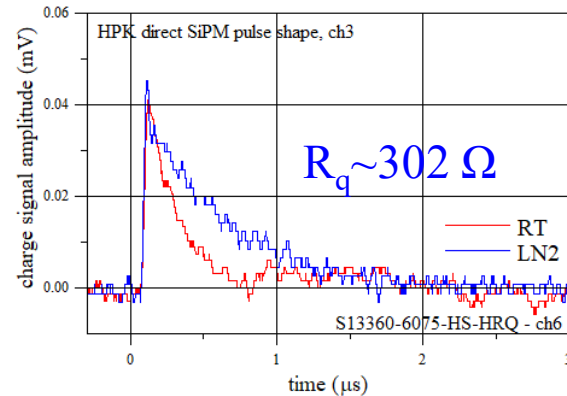
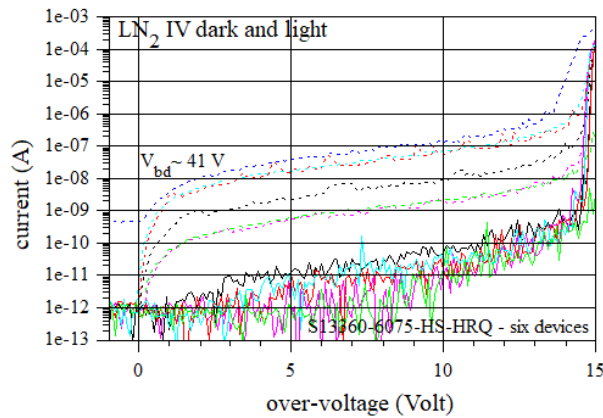
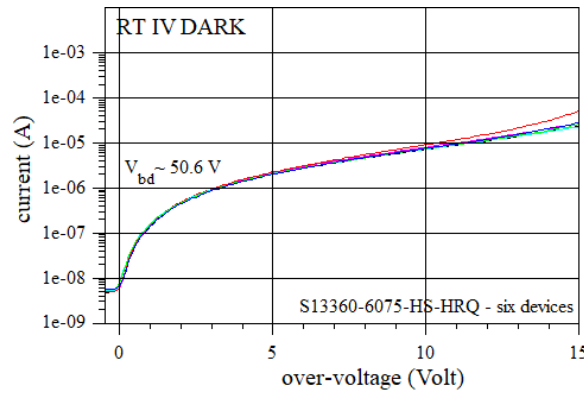
**FBK triple-trench**

area	6x6 mm <sup>2</sup>
pixel size	50 μm
# of pixels	11188
$V_{bd}$ (RT, LN2)	31 V, 27 V
Capacitance	2.6 nF

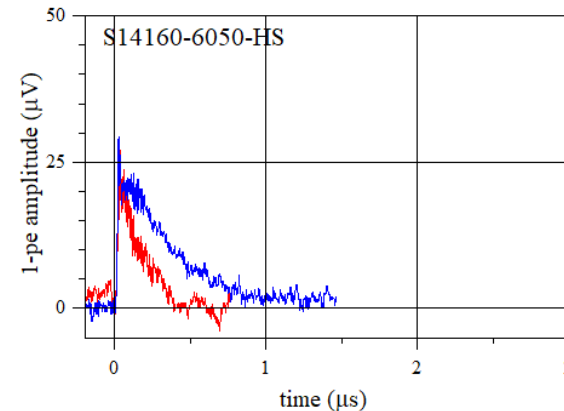
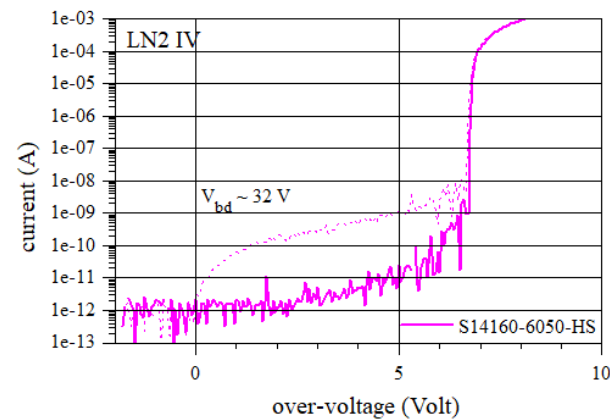
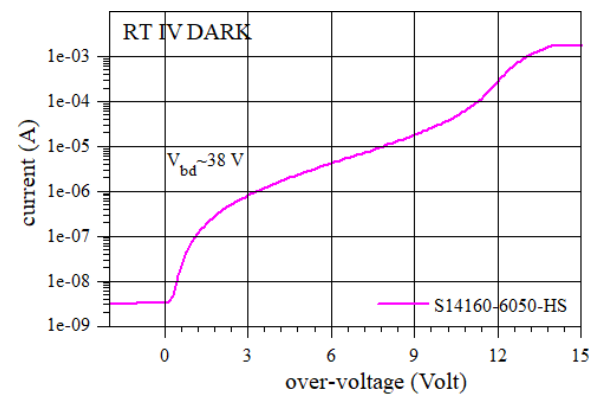
### DUNE S13360-6050-HS-HRQ high $R_q$ , normal $V_{bd}$



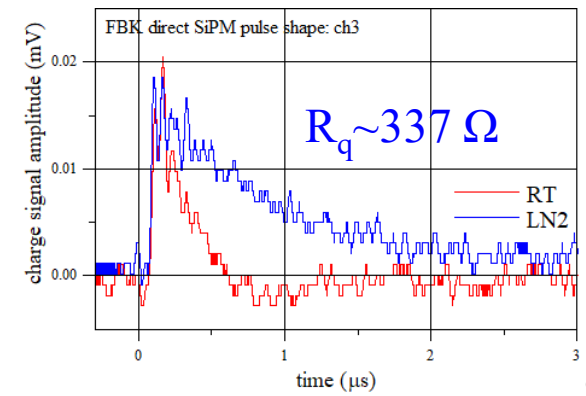
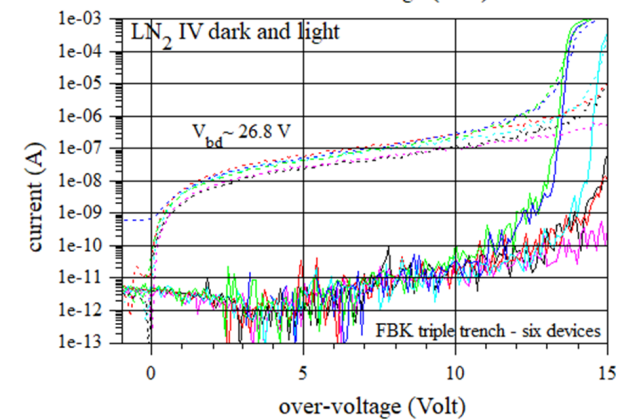
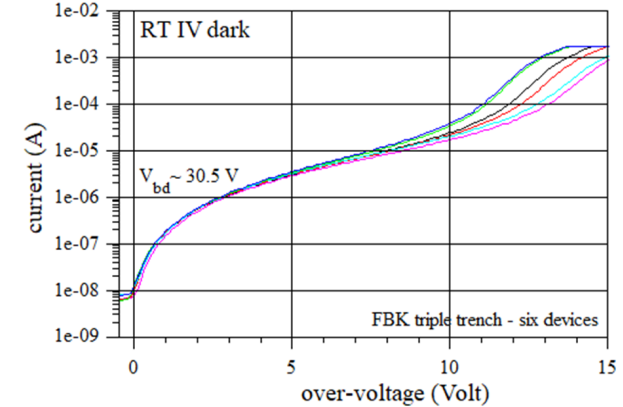
### DUNE S13360-6075-HS-HRQ high $R_q$ , normal $V_{bd}$



### ProtoDUNE FNAL S14160-6050-HS low $V_{bd}$



### DUNE FBK triple-trench 50μm low $V_{bd}$





# nEXO SiPM light readout: requirements

- The energy, timing, and event resolution must be met in order to achieve the  $10^{28}$  year half-life sensitivity to  $0\nu\beta\beta$ .
- For a 6% light collection efficiency,  $\sim 6240$  photoelectrons will distribute over  $\sim 4.6$  m<sup>2</sup> surface of the photon detectors.
- A SiPM sub-array of 6 cm<sup>2</sup> will detect approximately *one photon on average*.
- The photon readout electronics must be able to efficiently detect and *identify single photoelectron events*.

Parameter	Value	Comment
Signal range [pe <sup>-</sup> ]	100 pe	Need a large dynamic range, simulation shown $\sim 100$ pe can be captured in a single channel.
SNR for 1-pe <sup>-</sup>	> 15	ensure a negligible accidental rate due to electronics noise compared to the SiPM dark noise rate
1-pe energy resolution	< 0.1 pe	To satisfy the nEXO energy resolution requirements.
Timing resolution	< 100 ns	With a dynamic range of 100 pe, a $\pm 3\sigma_t$ coincidence window, would satisfy the nEXO energy resolution requirements.
Readout non-linearity	< 1%	strict integral linearity requirement from the magnitude of the electronic readout response to the SiPM charge signal response
Max. event rate [events/s]	$4 \times 10^3$	calibration by radioactive sources, DCR, photon flash

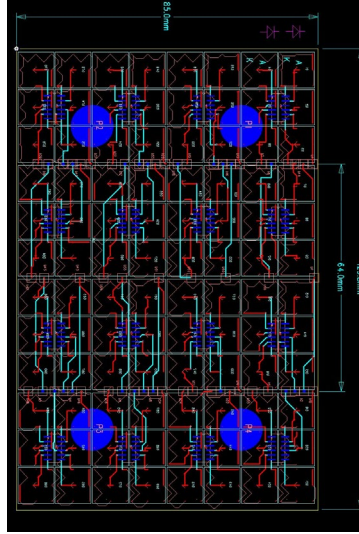
# nEXO SiPM Light Detector Readout

6 cm<sup>2</sup> SiPMs  
3P2S



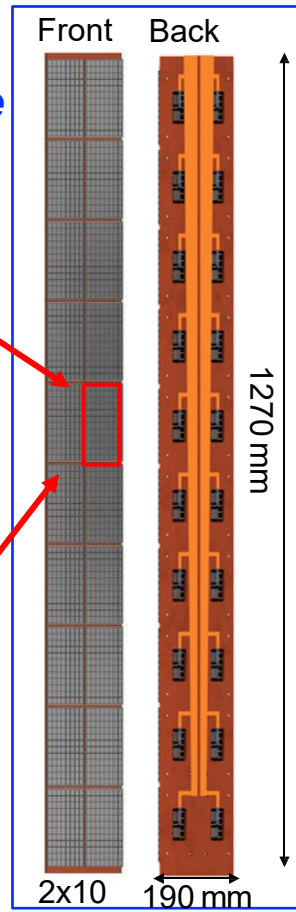
TSV  
75 μm/pixel  
SiO<sub>2</sub> carrier

96 cm<sup>2</sup> SiPMs tile

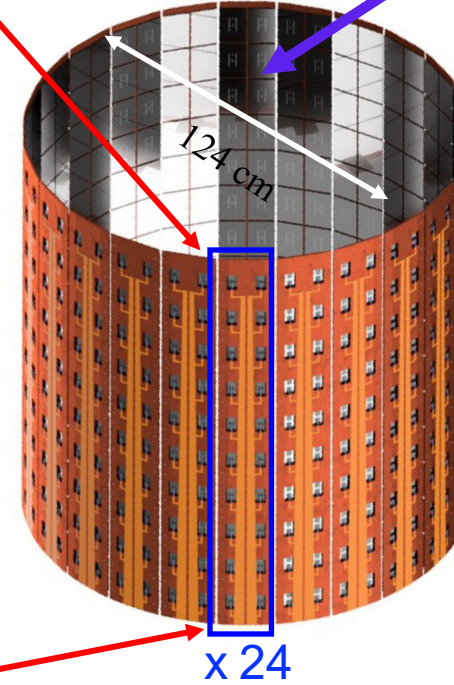


16 channels  
3P2S connection

Stave



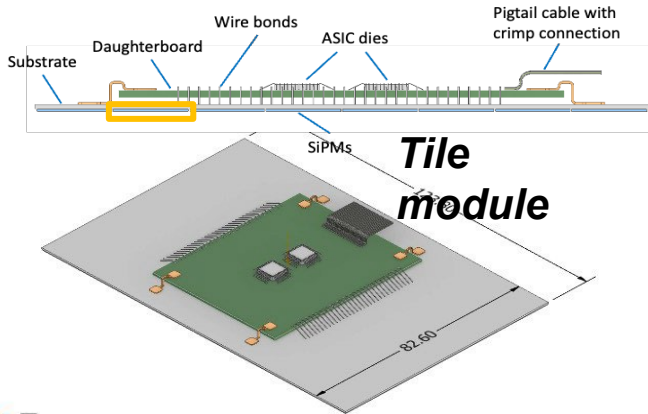
SiPM 'bird cage'  
 $\lambda=175$  nm



Total tiles: 480  
24x(2x10)

Total 6 cm<sup>2</sup> subarrays: 7680  
480x16

Total SiPM area: 4.6 m<sup>2</sup>  
7680x6 cm<sup>2</sup>



Tile  
module

Technology		HPK	FBK
$V_{operating}$ (RT)	[V]	50	30
$C/area$ [nF/cm <sup>2</sup> ]		3.5	8.5
$C$ (6 cm <sup>2</sup> ) / channel [nF]		21	51
$C$ (8P2S) [nF]		5	12.5
$V$ (2S)	[V]	100	60

*Very large subarray capacitance/channel*

# nEXO SiPM selection

## Vendor selection criteria:

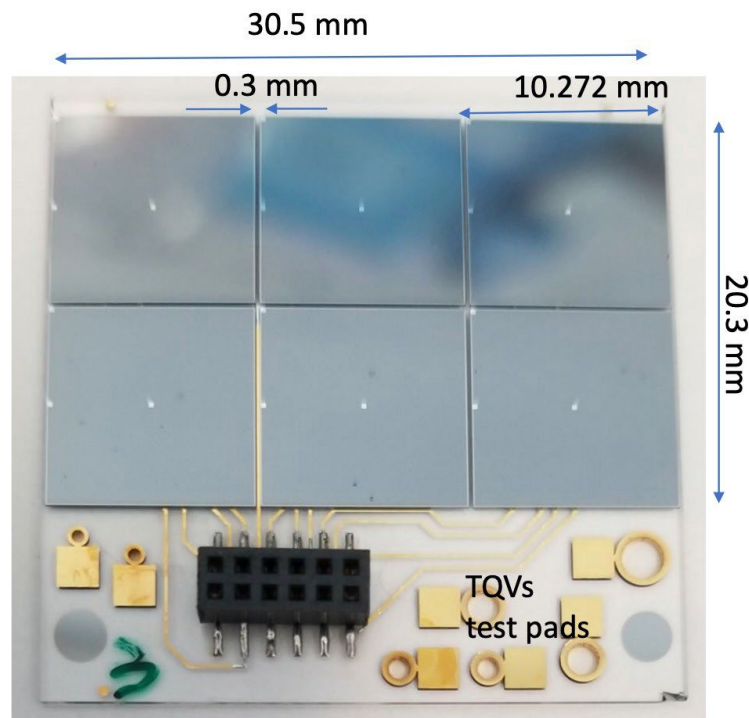
1. Meets nEXO radioactive background and PDE, CA, DCR requirements
2. TSVs are available to avoid need for wirebonds on tile module front side
3. Time scale for production and testing requirements does not delay the overall nEXO development path
4. High uniformity of devices in realistic final production, to minimize testing and device selection requirements during assembly
5. Cost (including risk) minimized while meeting criteria 1-4 above.

D. Moore, Jan. 2022 nEXO Collaboration Meeting

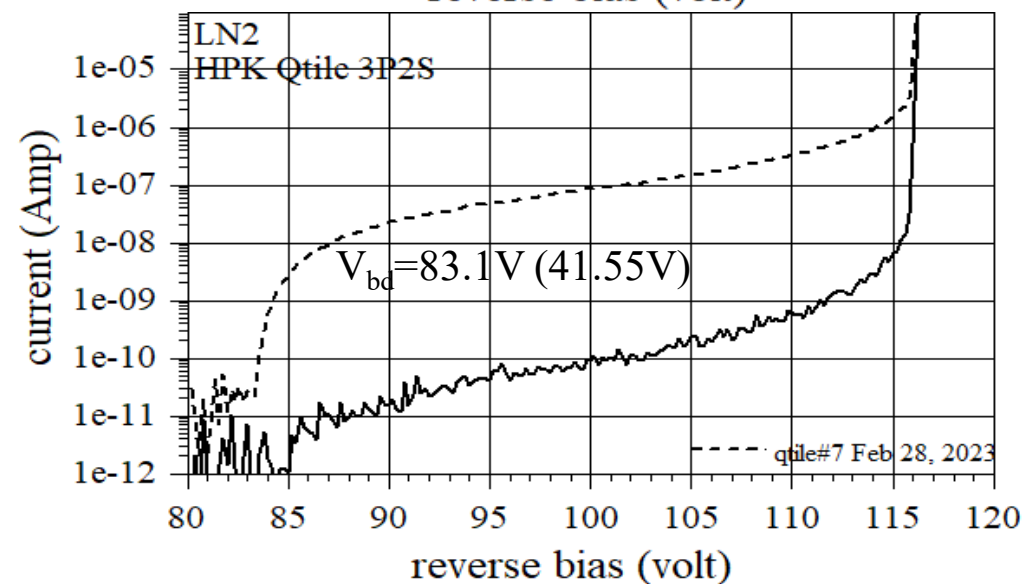
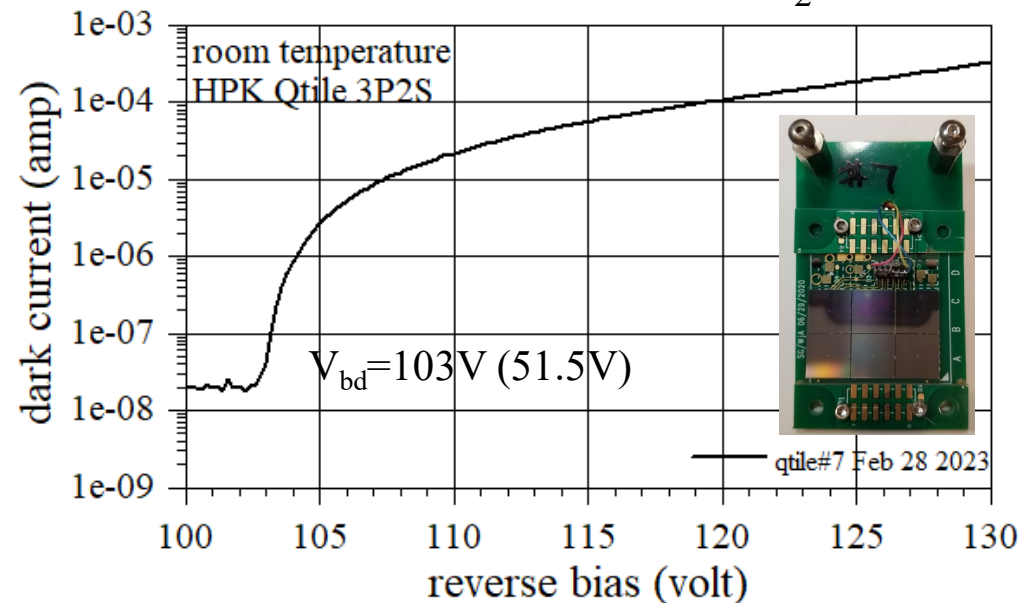
175 nm, 165K	HPK	FBK
SiPM radioactive background <0.5%	yes	yes
PDE >15%	yes	yes
DCR < 10 Hz/mm <sup>2</sup>	yes	yes
Correlated noise <0.4 pe	yes	yes
1 cm <sup>2</sup> array size	yes	Yes, but have issues
TSV	yes	not yet
V <sub>bd</sub> uniformity	in progress	unknown
prototype issue	packaging	IV

# HPK 6 cm<sup>2</sup> SiPM silica tile: IV

HPK 6x1 cm<sup>2</sup> SiPMs with TSVs

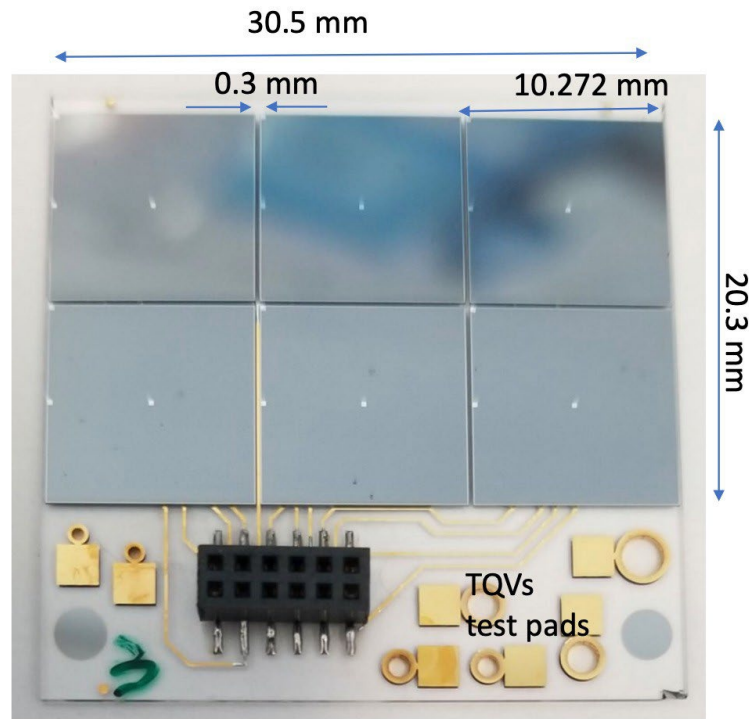


3P2S IV: room & LN<sub>2</sub>



# HPK 6 cm<sup>2</sup> SiPM silica tile: PDE

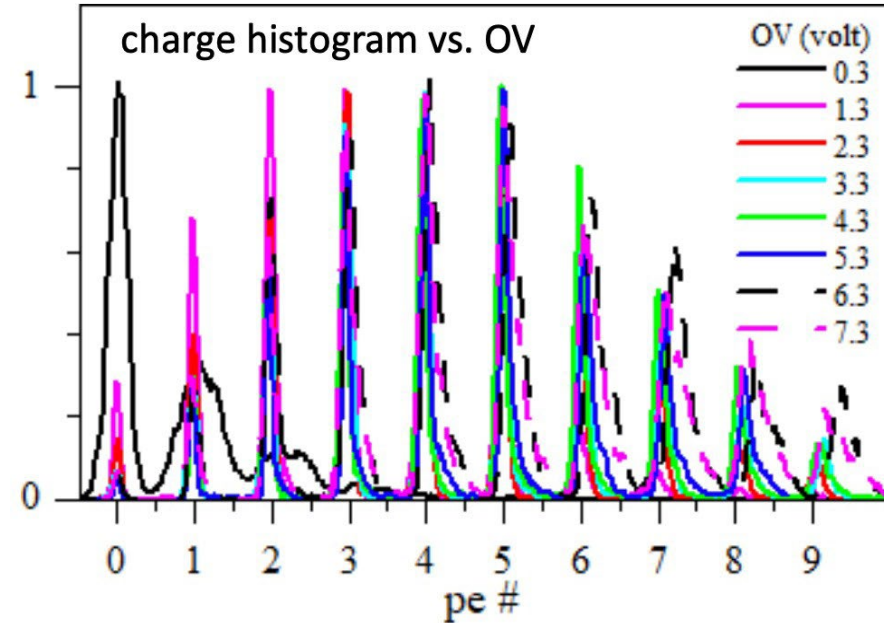
HPK 6x1 cm<sup>2</sup> SiPMs with TSVs



HPK SiPMs with TSVs perform well.

Need to verify PDE at 175 nm and test in LXe

PDE data (1ns pulse, 268 nm)

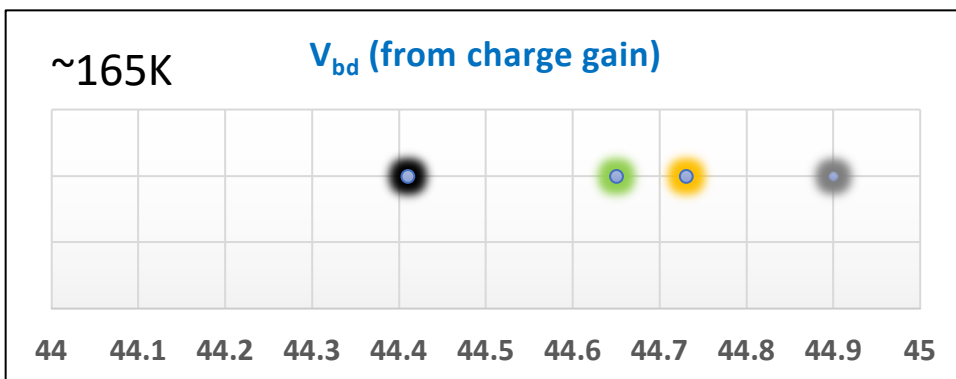
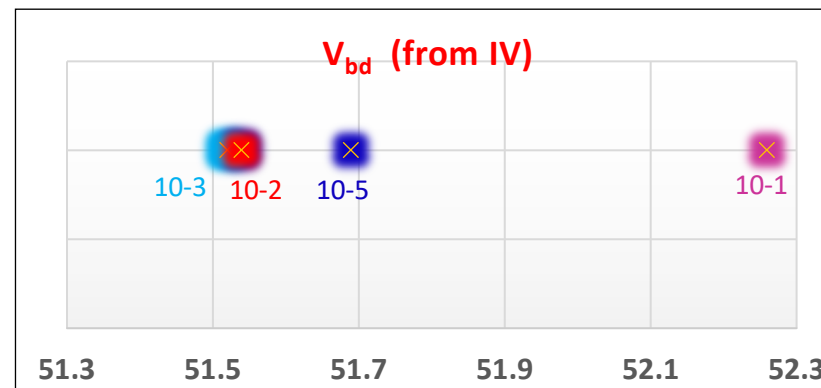
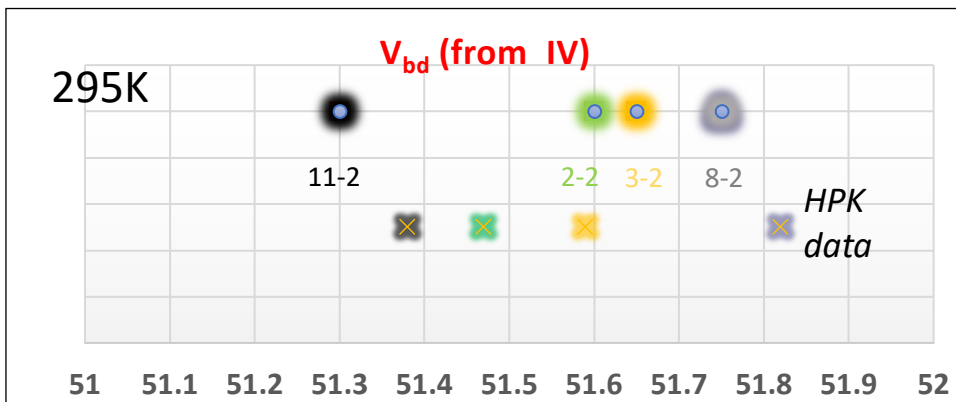


Summary of data

~4V OV	unit	room	cold ~155K
V-breakdown	Volt	51.5	44.5
overvoltage span	Volt	>15	>15
R_quench	Ω	23	31
Charge gain	x10 <sup>6</sup>		1.48
DCR	Hz/cm <sup>2</sup>		~20
1-pe resolution	%		3.7
CA	pe		0.05
μCell capacitance	fF	243	233
μCell capacitance	nF/cm <sup>2</sup>	4.3	4.11
PDE (268 nm)	n/c		0.165

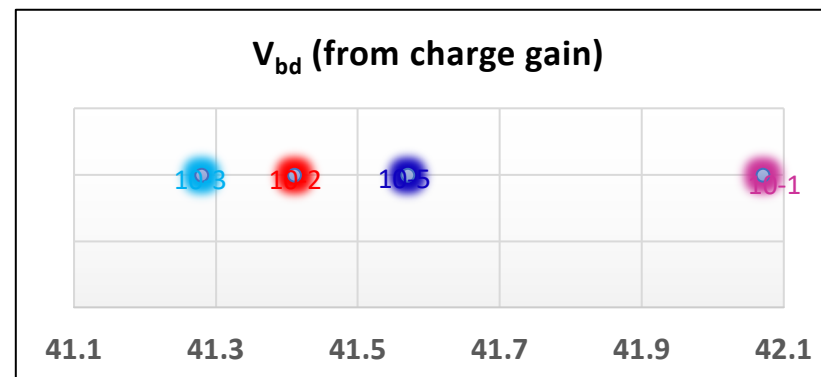
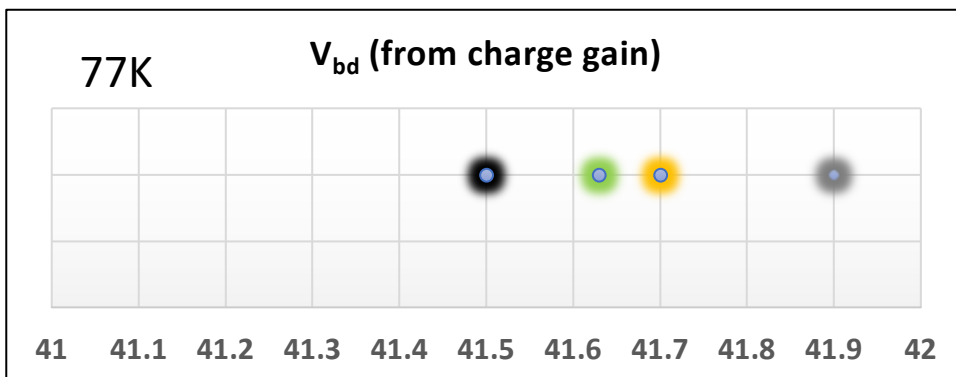
previous PDE measurements  
~0.18 (268 nm)  
~0.22 (175 nm)

# HPK 6 cm<sup>2</sup> SiPM silica tile: *correlation of $V_{bd}$ from RT to LN<sub>2</sub>*



device # - channel #

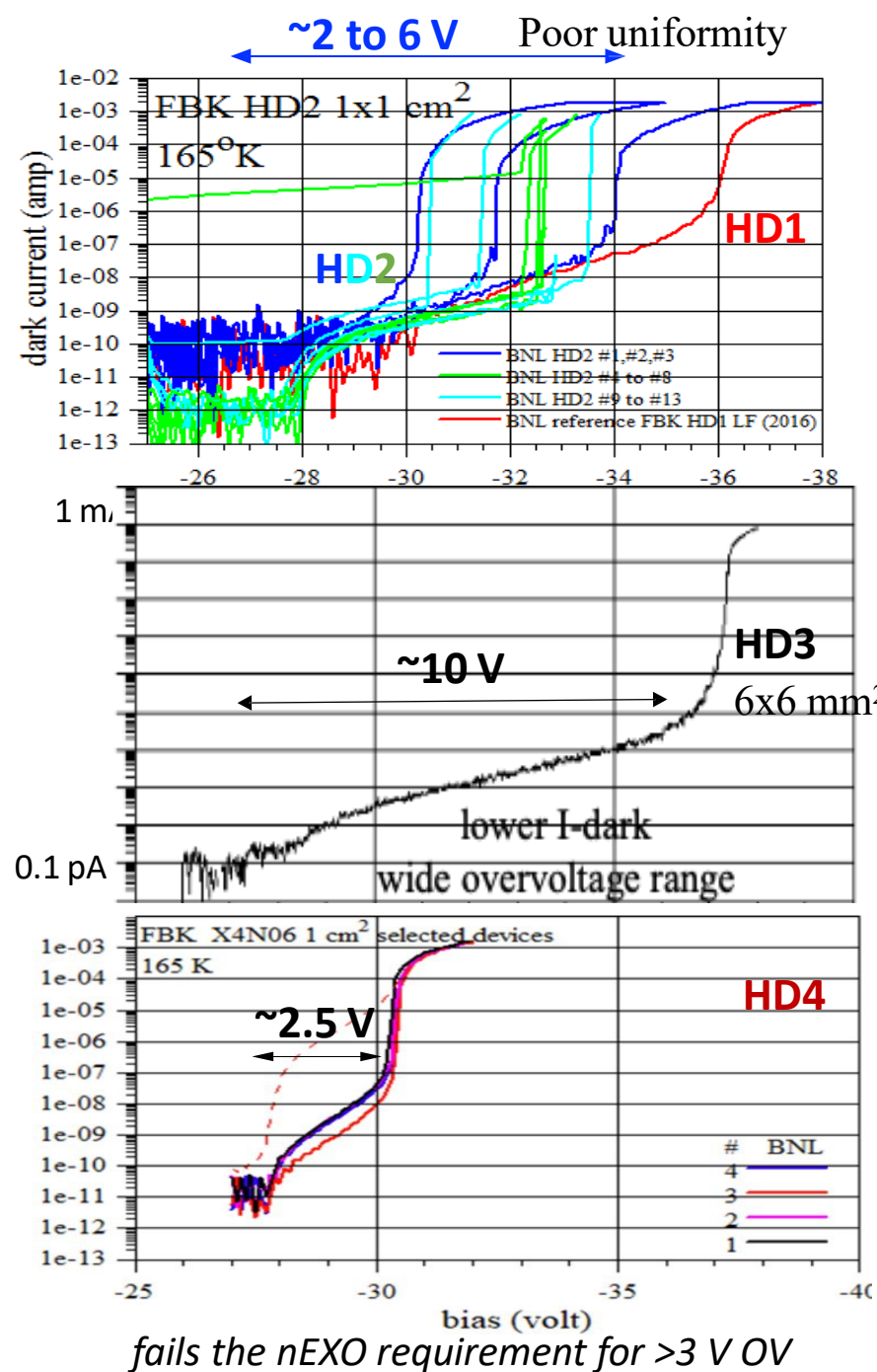
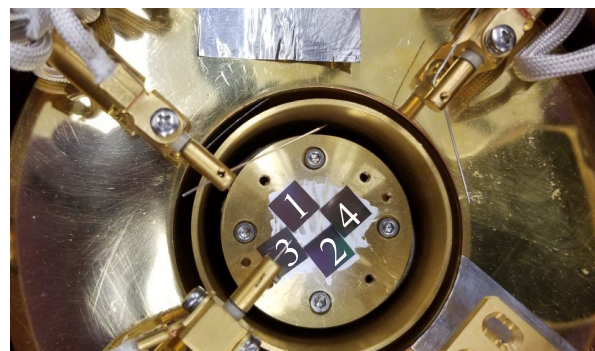
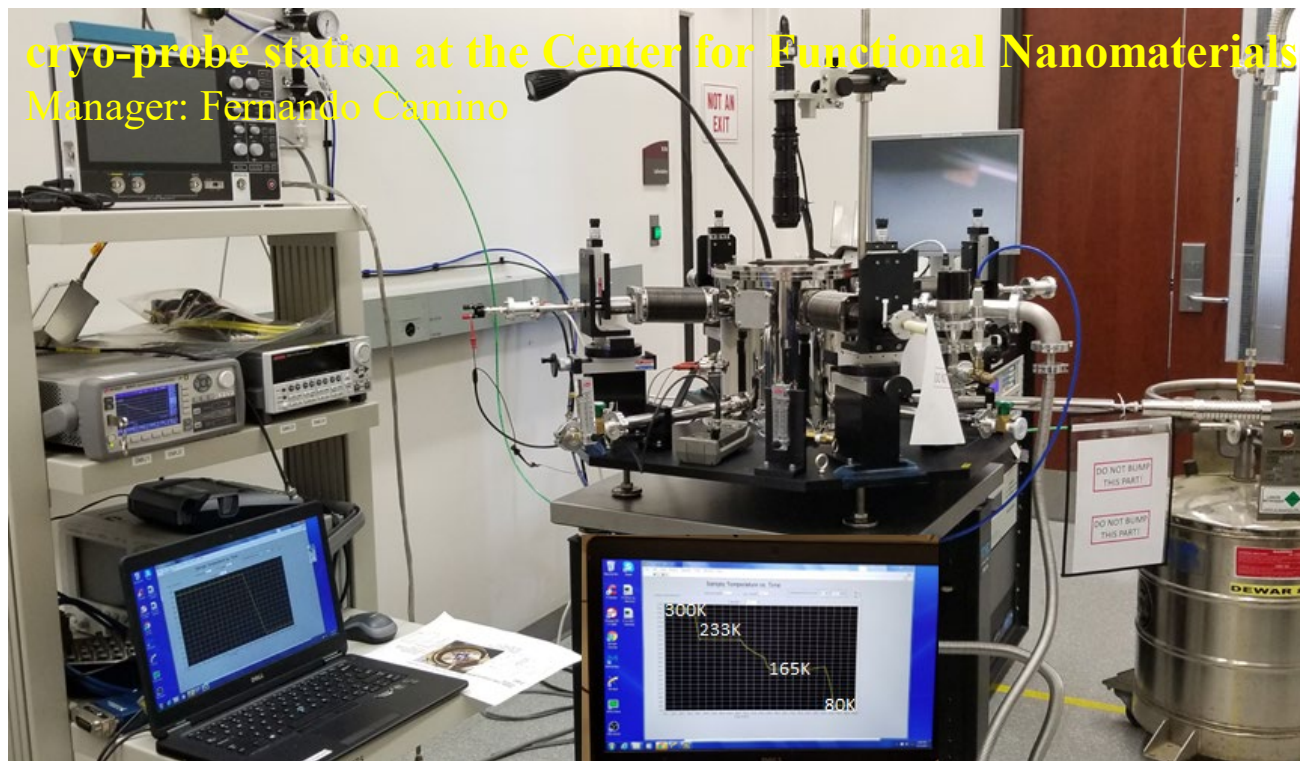
$V_{bd}$  determined from extrapolated zero-charge gain measurement



- larger sample size continue to show evidence of  $V_{bd}$  correlation
- *Charge gain match of SiPM tiles may be projected from RT to cold*

# FBK prototypes: IV at RT, 233K 165K & 80K

cryo-probe station at the Center for Functional Nanomaterials  
 Manager: Fernando Camino



# **Charge Readout concept: weak coupling to amplifier using HPK SiPM Minitiles**

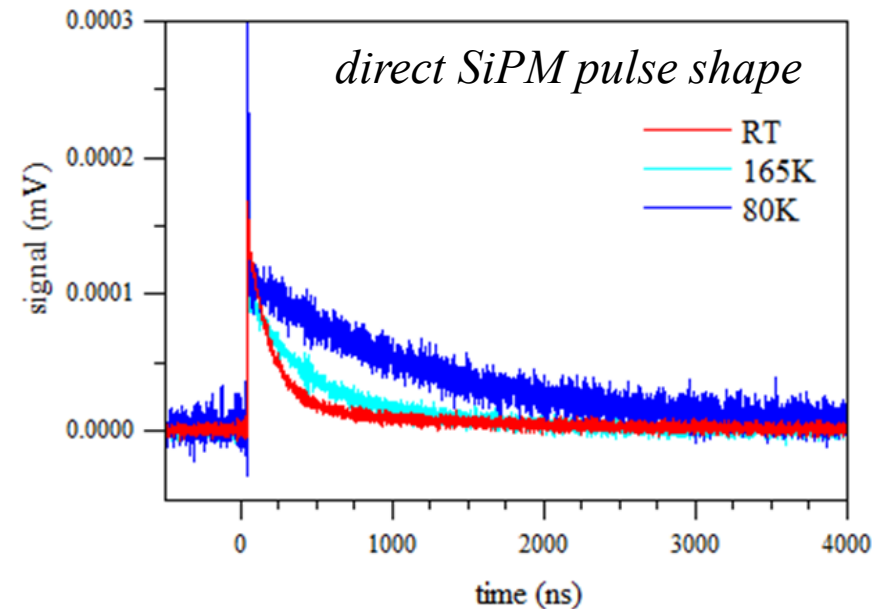
*Thomas Tsang, Shanshan Gao, Sergio Rescia, Hucheng Chen, and Veljko Radeka*

2021 IEEE/MIC



To know the number of detected photons, the charge of the signal must be measured.  
two most common approaches:

- *Charge integration*
- Amplitude measurement

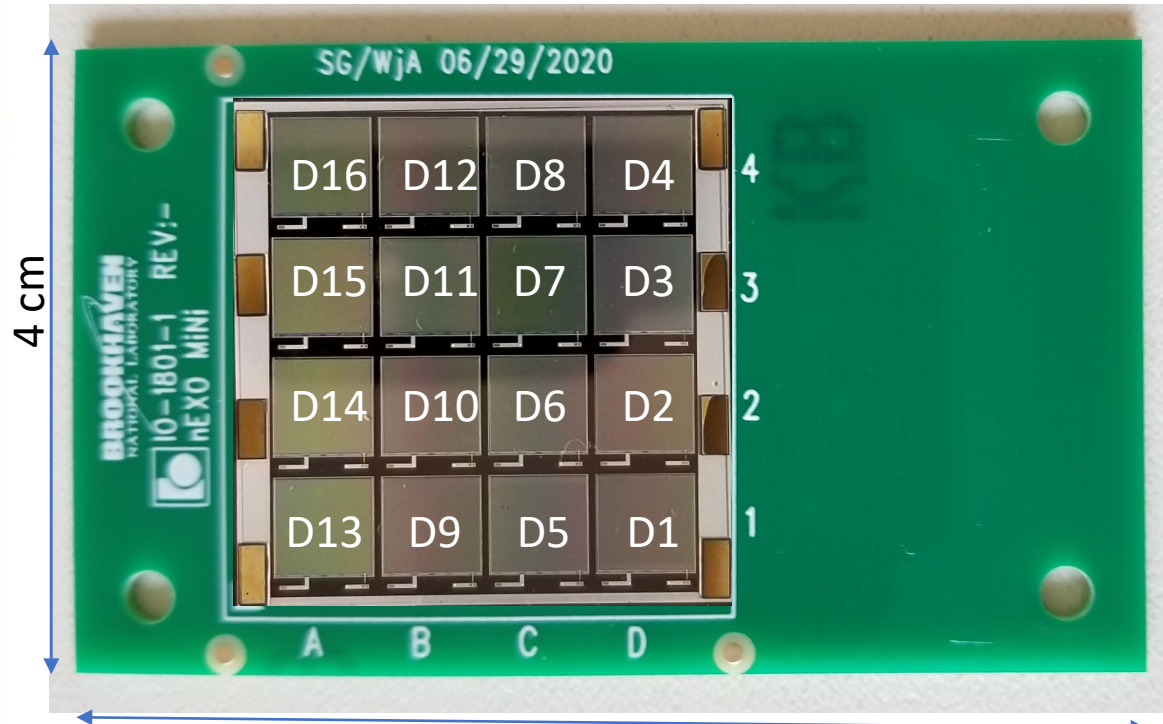


Both methods have their advantages and disadvantages.

# HPK SiPM Minitile arrays

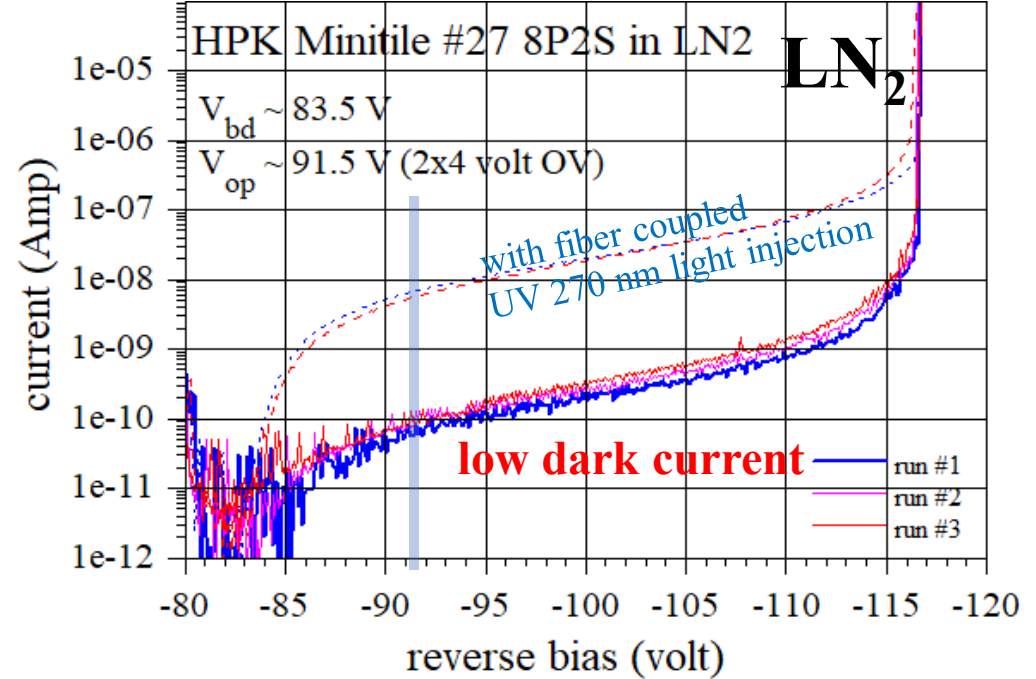
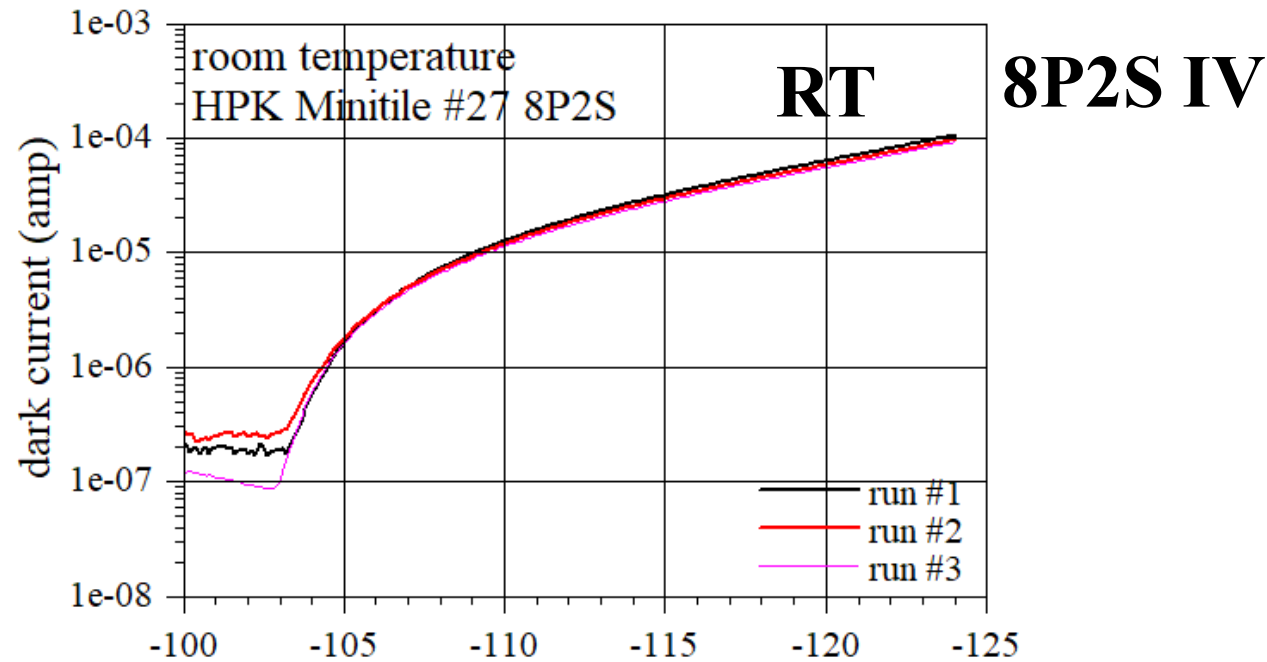
S13775-9121 [4x4x(0.6 cm)<sup>2</sup>]

HPK minitile board



6.8 cm

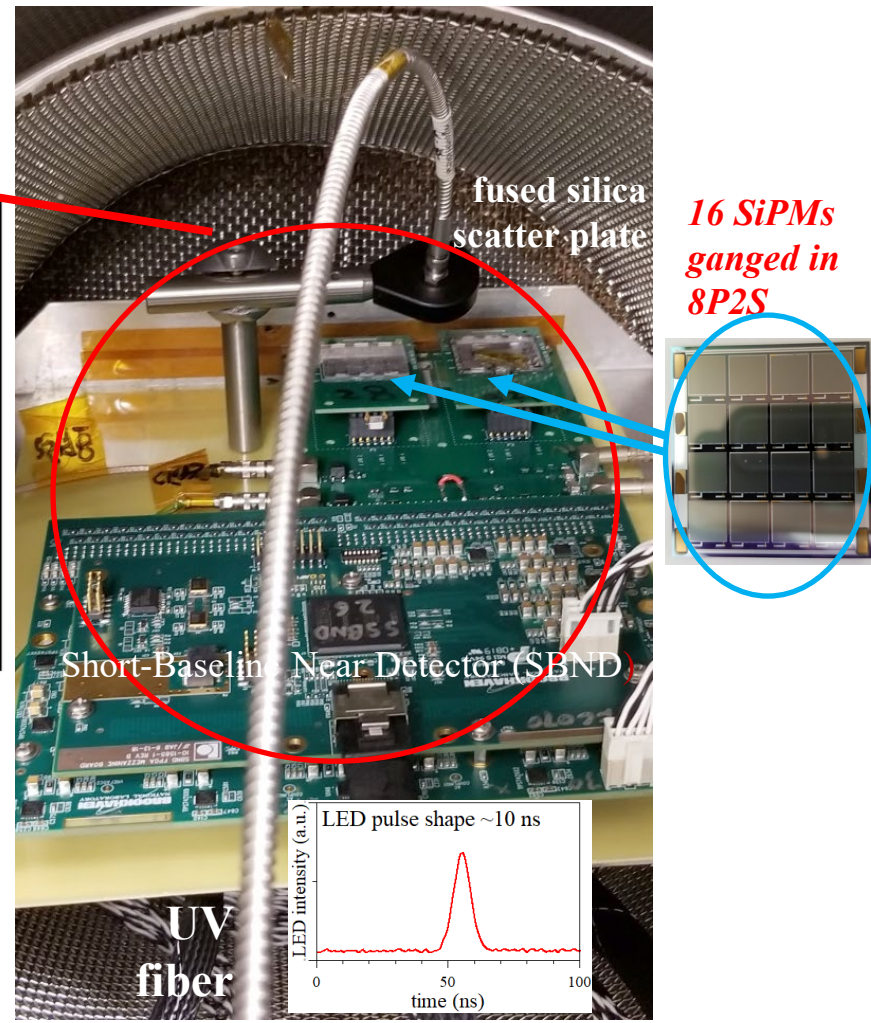
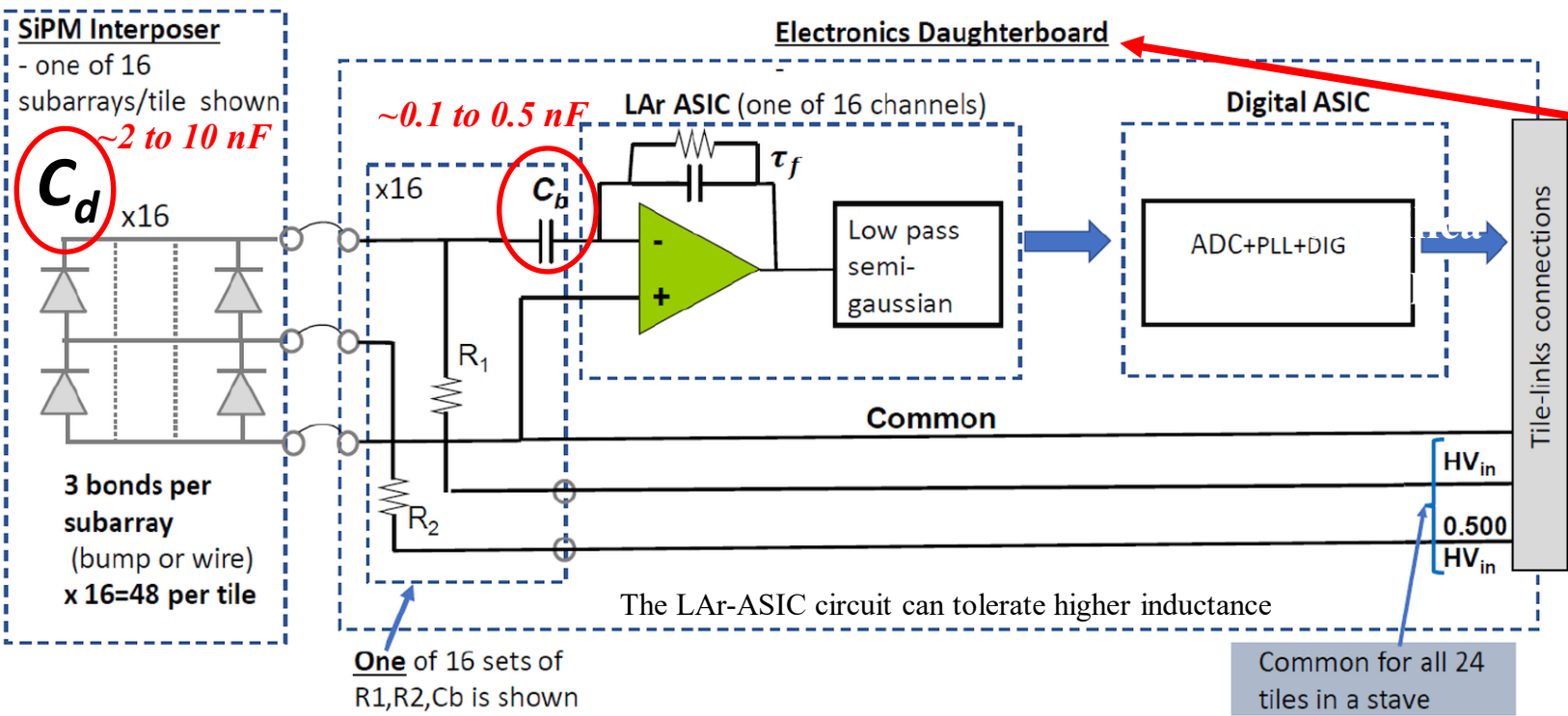
active area=5.76 cm<sup>2</sup>  
 $N_{\text{cell}} = 16 \times 13923 = 222768$  pixels (50  $\mu\text{m}$  pixel)  
 $C_{\mu\text{cell}}(\text{RT}) = 86$  fF  
 $C_{\text{Terminal}}(\text{RT}) = 1.2$  nF (3.3 nF/cm<sup>2</sup>)  
 $C_{\text{total}}(16\text{P}) \text{ SiPM tile} \sim 20$  nF  
 $C_{\text{total}}(8\text{P}2\text{S}) \text{ SiPM tile} = 4.8$  nF



*At ~4V OV  $I_{\text{dark}}$  (DCR) RT  $\rightarrow$  LN<sub>2</sub> drops  $\sim 10^{-5}$*

*Photoelectron spectroscopy, charge calibration,  
SiPM avalanche gain, electronics gain  
response to single and multiple photoelectrons  
both #27 and #28*

# Demonstration of readout concept: weak coupling to amplifier, $C_b \ll C_d$



## LArASIC P2:

16 **independent** ASIC input channels  
 peaking time: **1  $\mu$ s** (programmable 0.5, 1, 2, 3  $\mu$ s)  
 ASIC gain: **4.7 mV/fC** (programmable 7.8, 14, 25 mV/fC)  
 $C_{cal}$  = 185 fF  
 ADC sampling rate: 2 MS/s (0.5  $\mu$ s/time tick)  
 10 MHz ref. clock locked to the LED trigger & ADC sampling clock

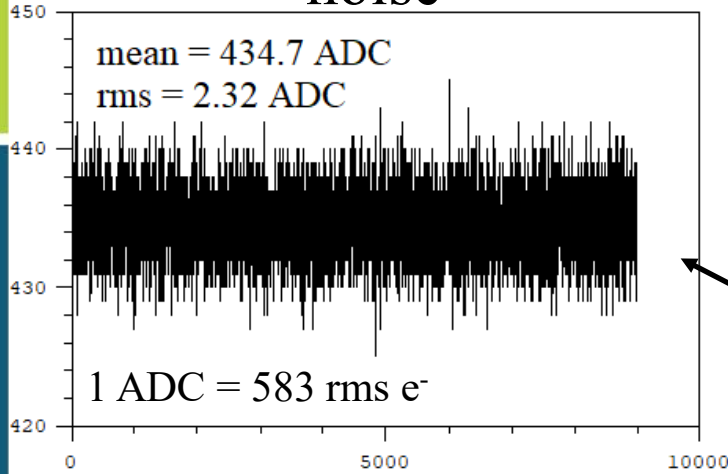
Reference: channel 0  
 Minitile 8P2S: channel 1, #28  
 Minitile 8P2S: channel 13, #27  
*only 2 ASIC channels are used.*

LArASIC readout by ADC and FPGA shown in the photo  
 Data streaming mode, 45sec/data  
 Data collection: LabView  
 Data analysis: Python

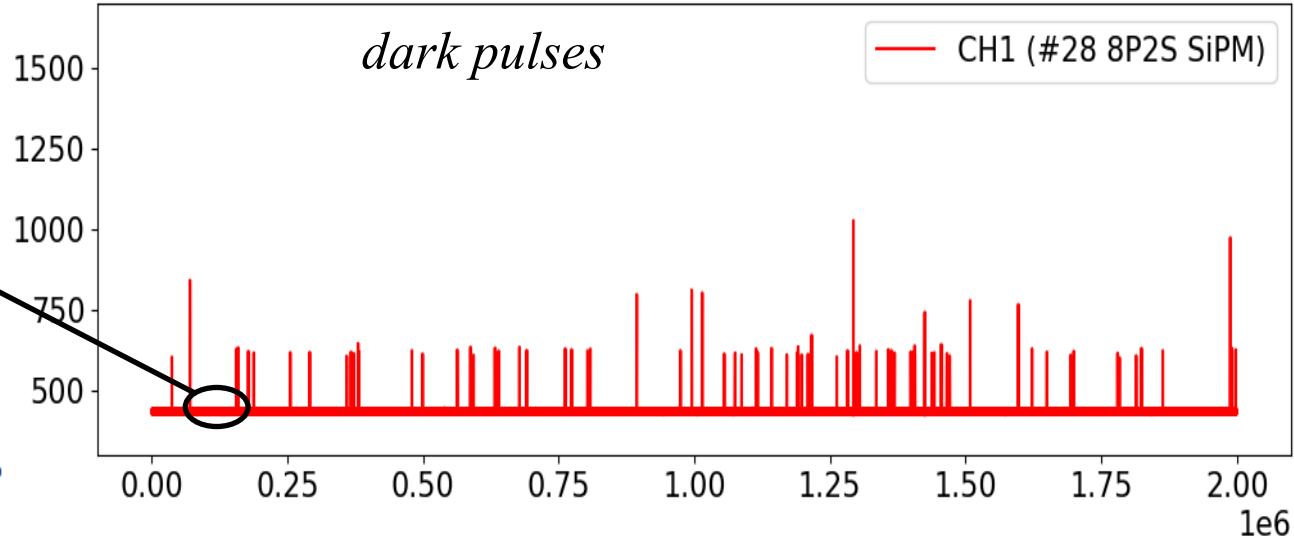


# in LN<sub>2</sub> @ 4.2 V OV 8P2S 4.8 nF: subset of raw signal trace (1 second)

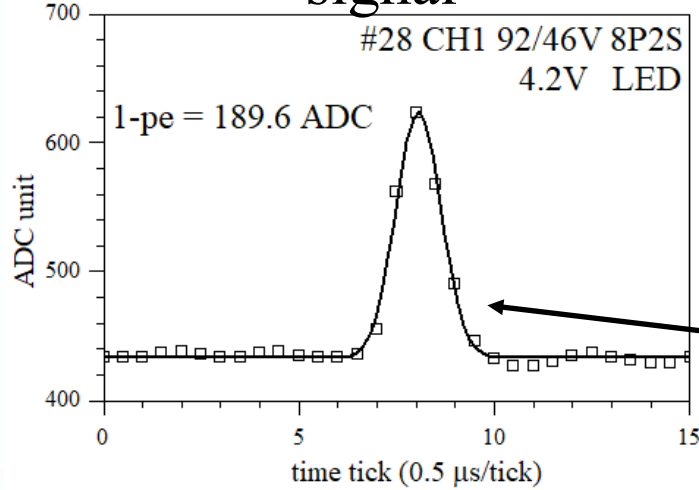
noise



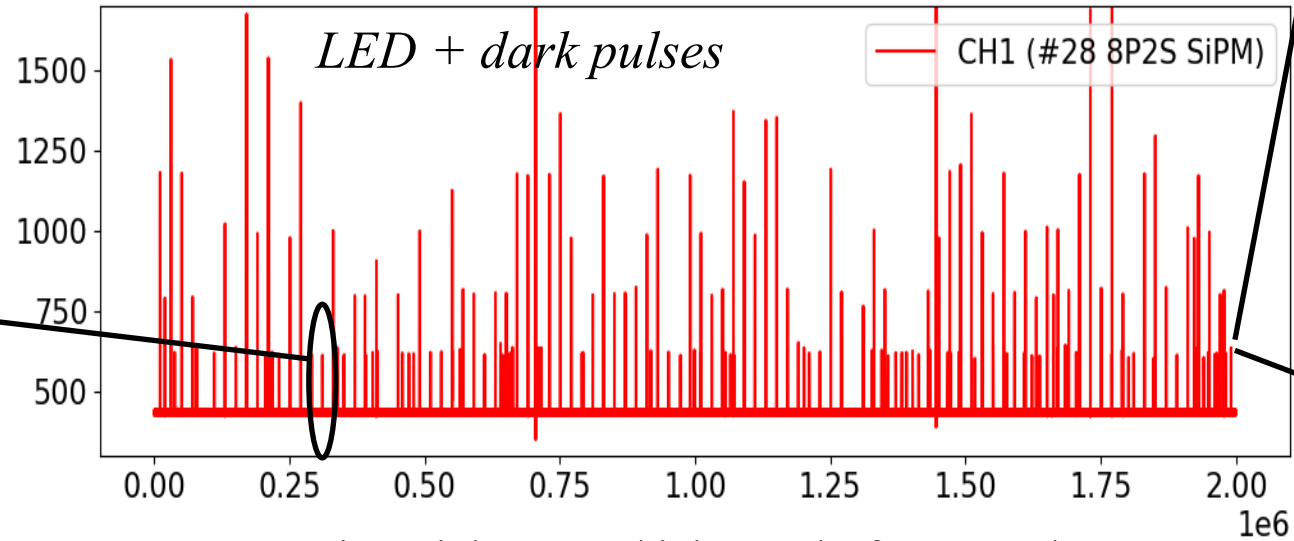
dark pulses



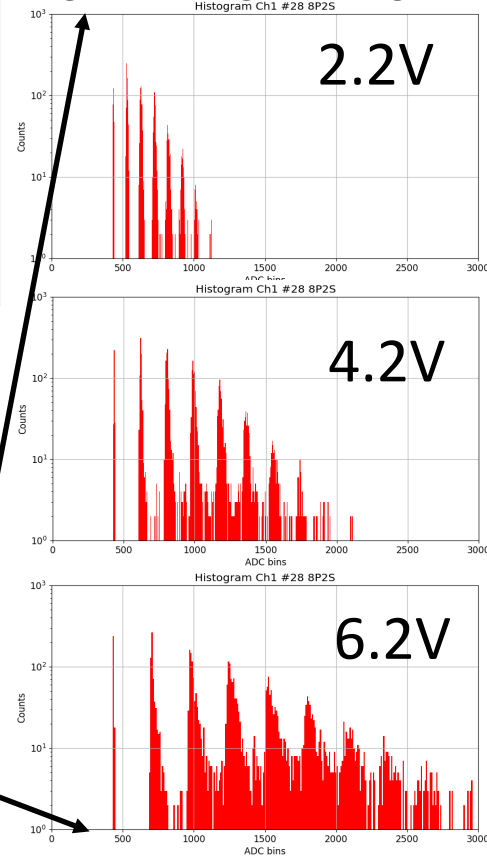
signal



LED + dark pulses



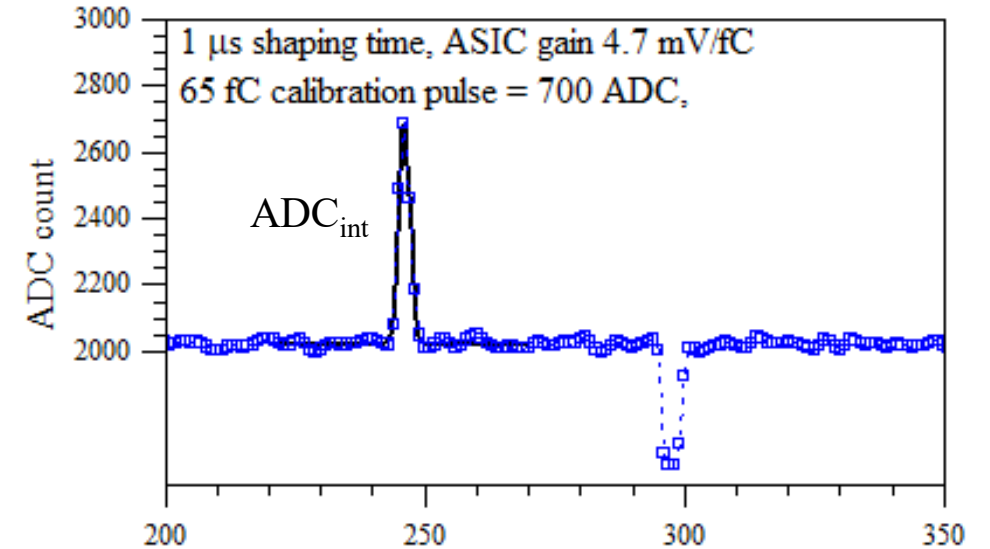
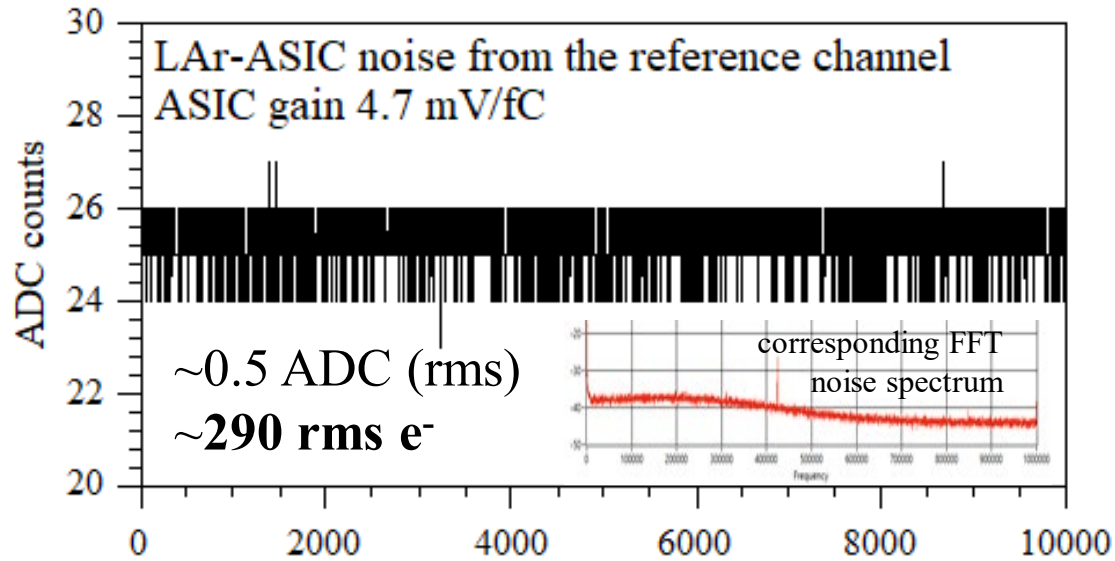
signal charge histogram



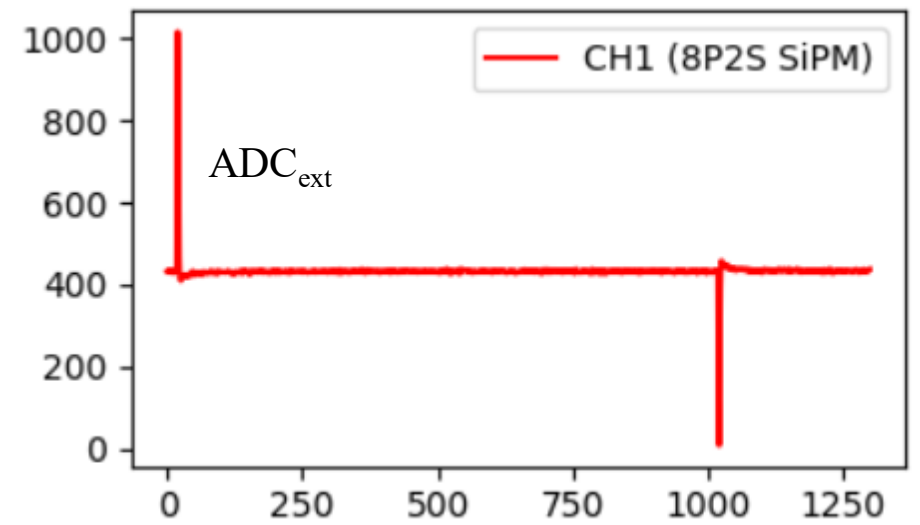
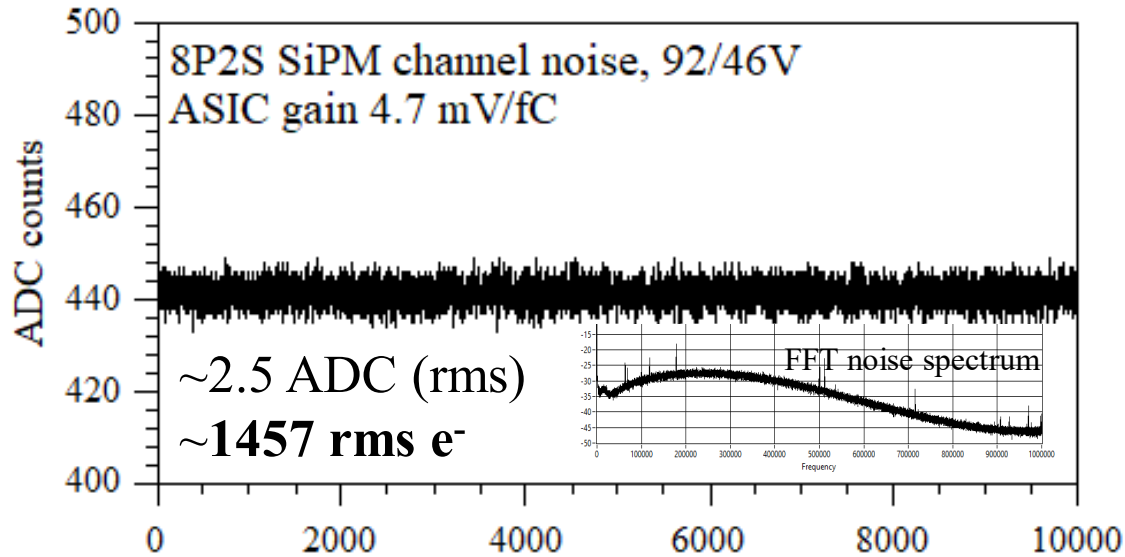
$$S/N = 189.6/2.32 \approx 82$$

# Electronic noise and Gain Calibration

Reference channel

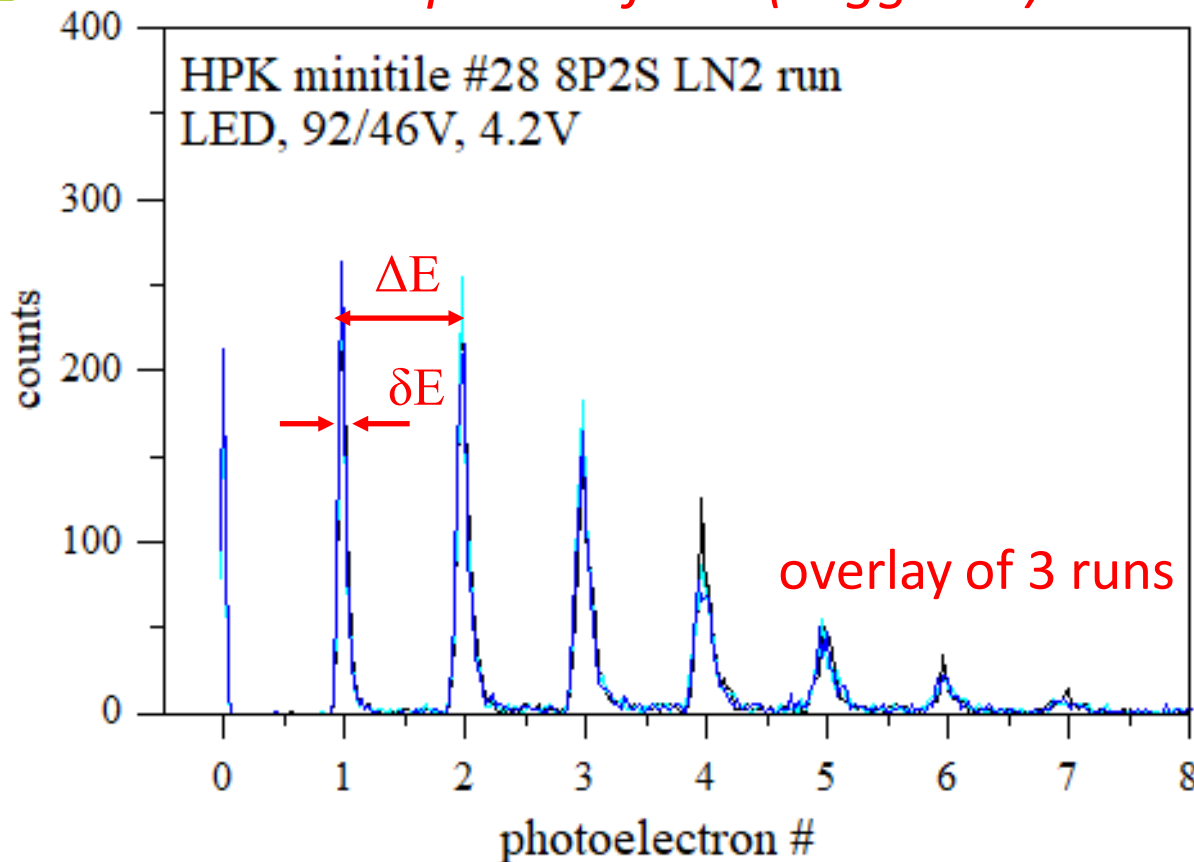


Signal channel



# in LN<sub>2</sub>: single-photoelectron charge histogram

LED photon flash (triggered)

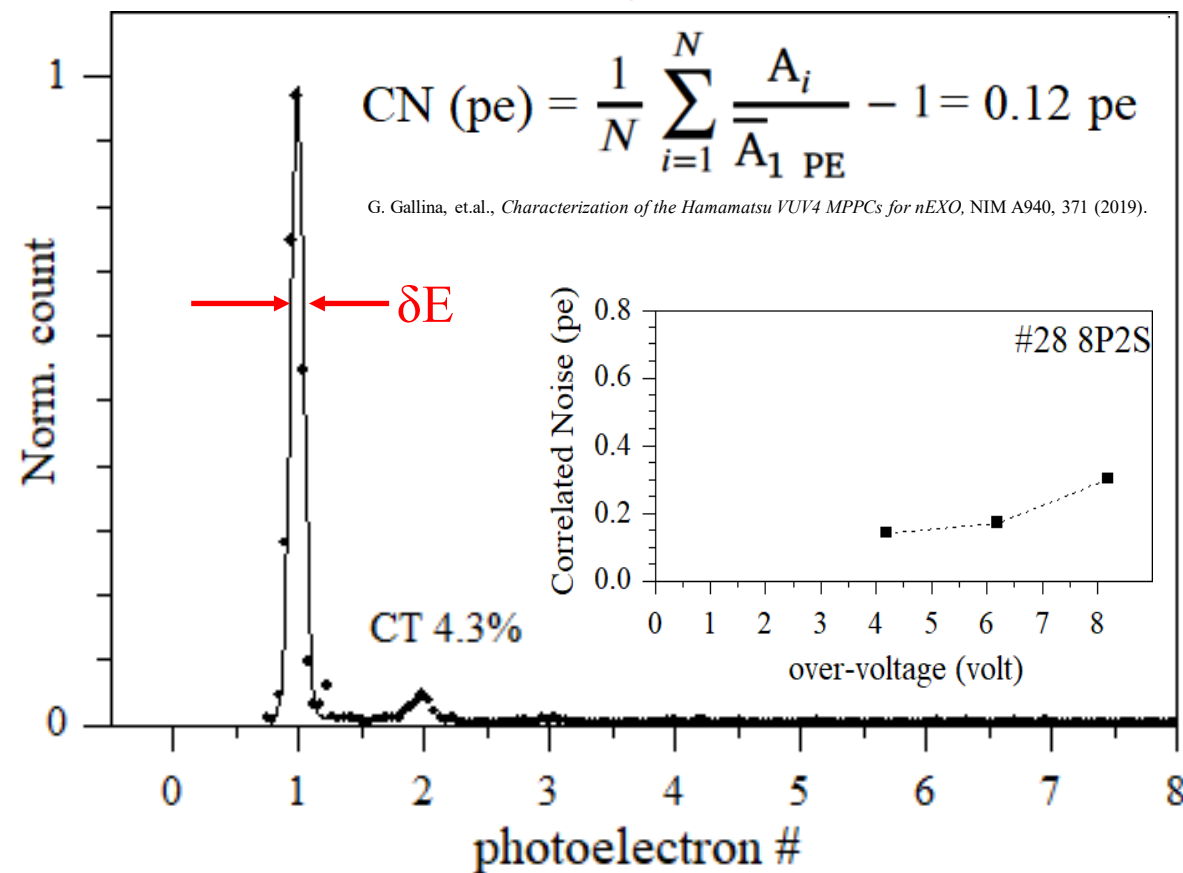


Photon rate: ~80 Hz (trigger rate 100 Hz)

1-pe resolution ( $\frac{\delta E}{\Delta E}$ ): <3.5% rms



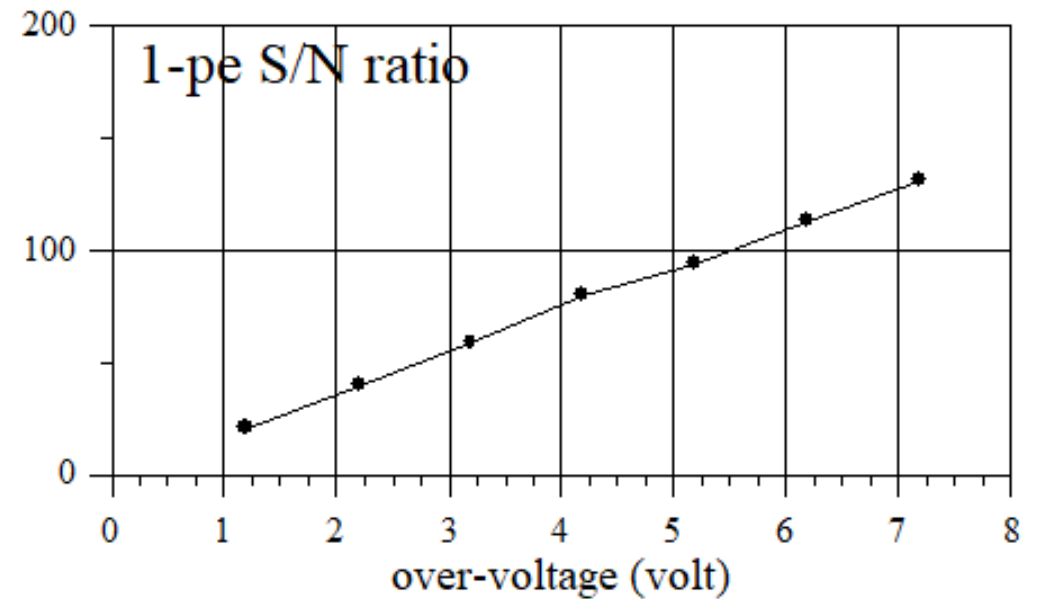
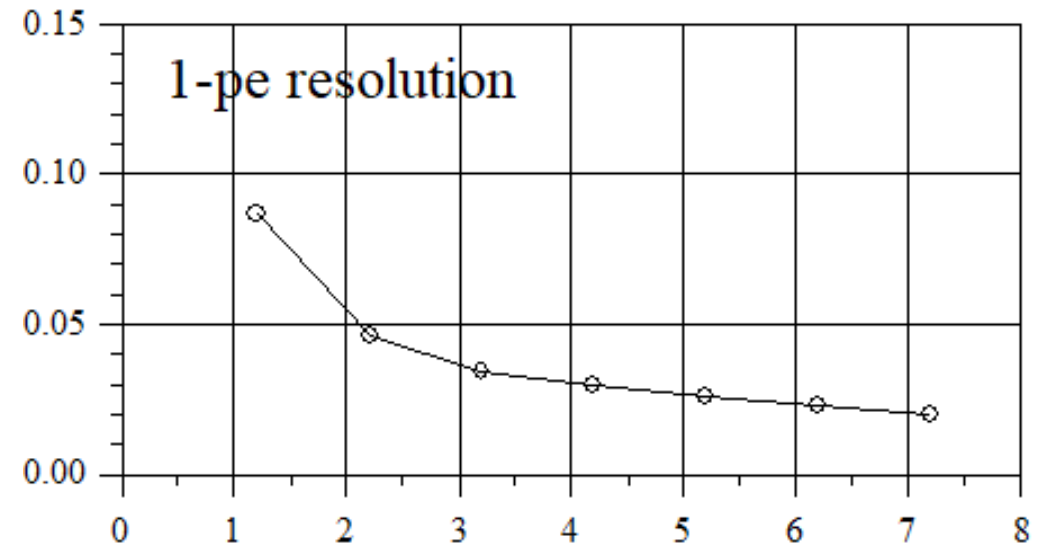
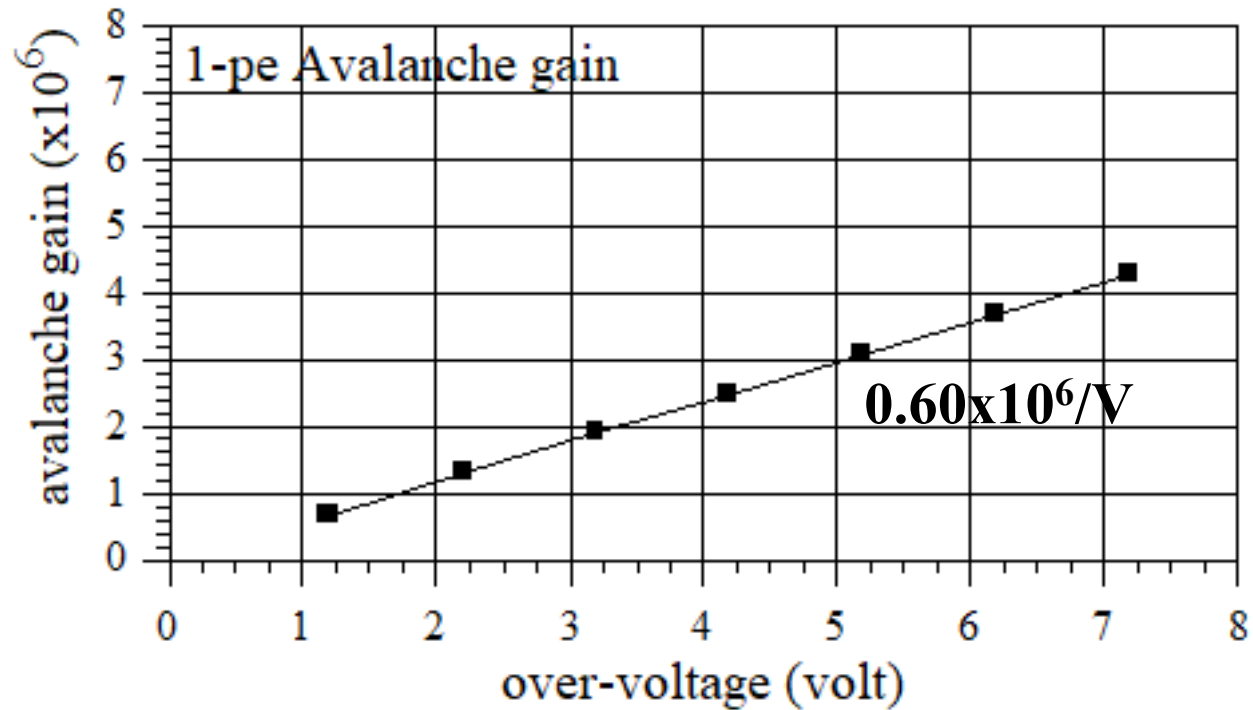
dark pulse



DCR: ~96 Hz (0.17 Hz/mm<sup>2</sup>)

1-pe resolution: ~5% rms

# Avalanche gain, S/N, resolution (8P2S, 4.8 nF), in LN<sub>2</sub>



*Avalanche gain of both channels are similar*

$$\text{Avalanche gain} = \frac{C_{\mu\text{cell}}}{e} (OV)$$

$$C_{\mu\text{cell}} \sim 90 \text{ fF}$$

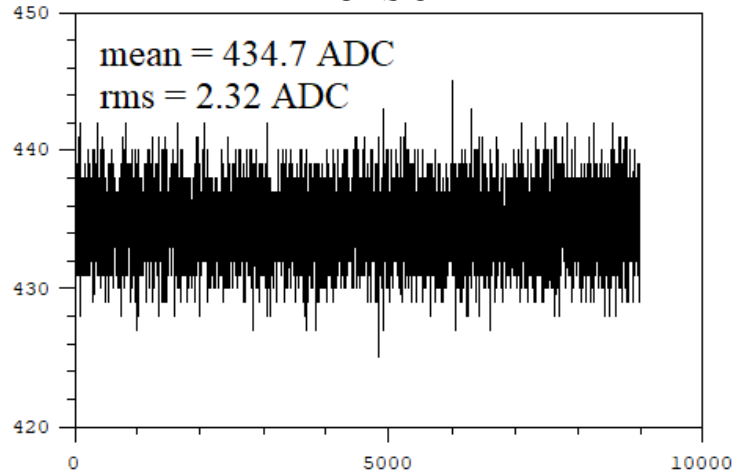
$$C_{\mu\text{cell}} = \epsilon_0 \epsilon_{\text{Si}} \frac{A}{d}, \text{ d=depletion thickness}$$



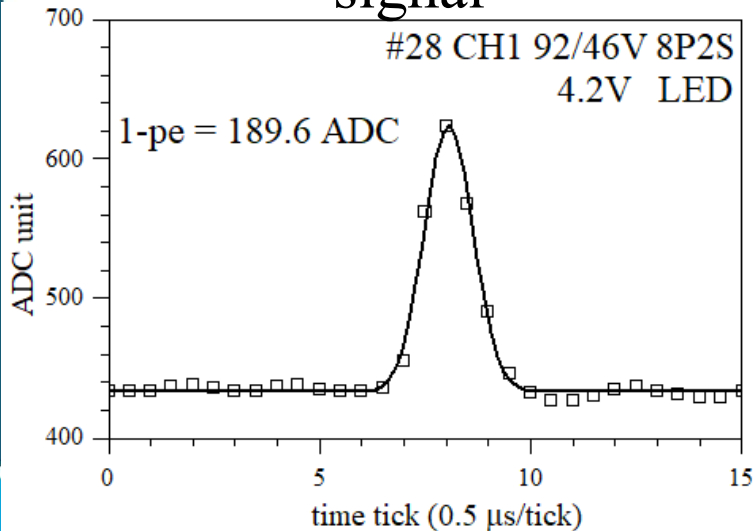
*timing resolution, and  
coincidence resolution*

# Minitile #28 8P2S in LN<sub>2</sub> @ 4.2 V : subset of raw signal trace (0.1 second)

noise

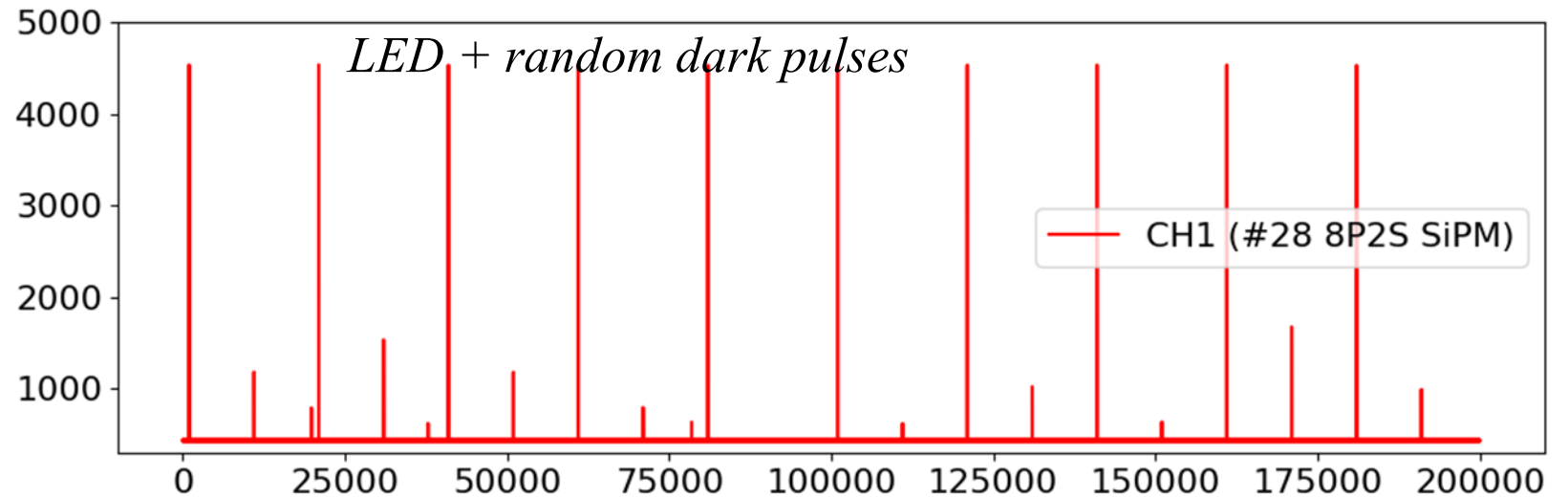
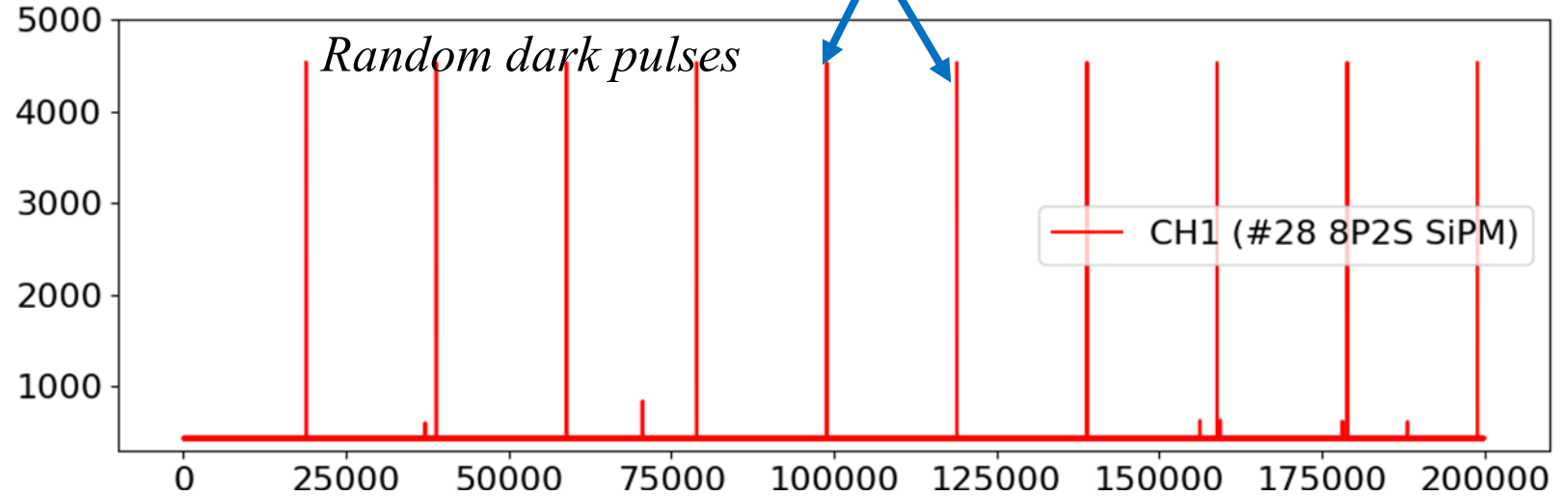


signal



$$S/N = 189.6/2.32 = 81.7$$

time marker added on bit #12 (trigger) 10 ms apart  
2 MHz sampling clock and 100 Hz LED trigger are locked

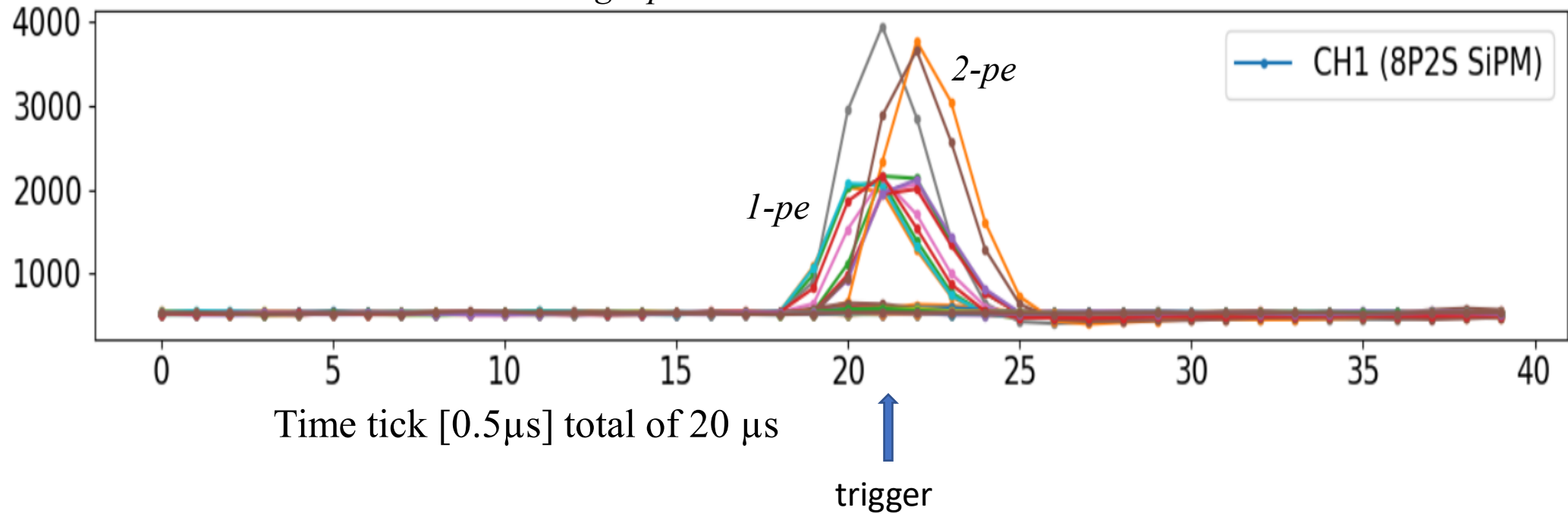


Time tick [0.5 μs/tick] total of 0.1 second

# time coincidence detection: 10 MHz reference clock lock OFF

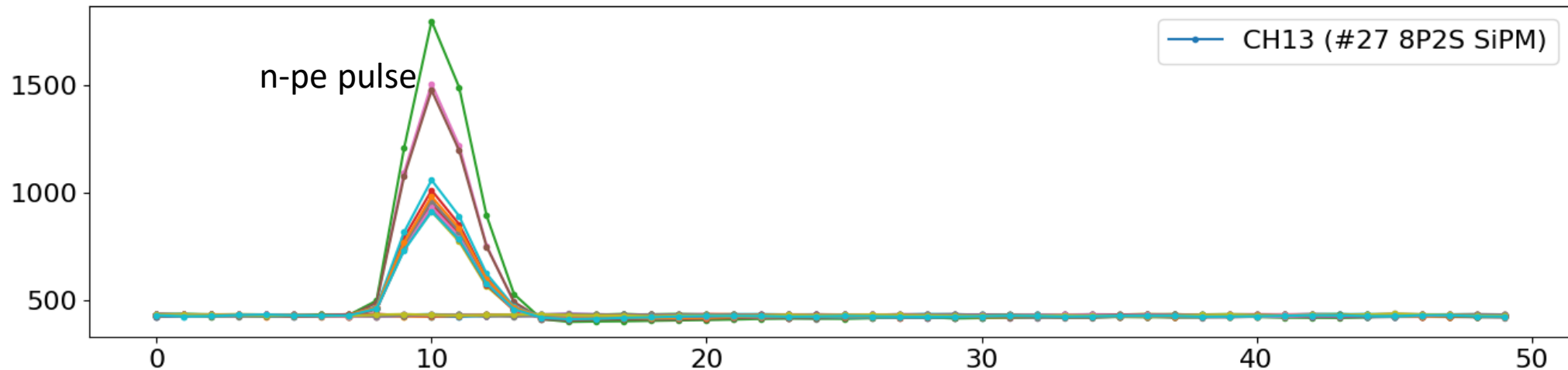
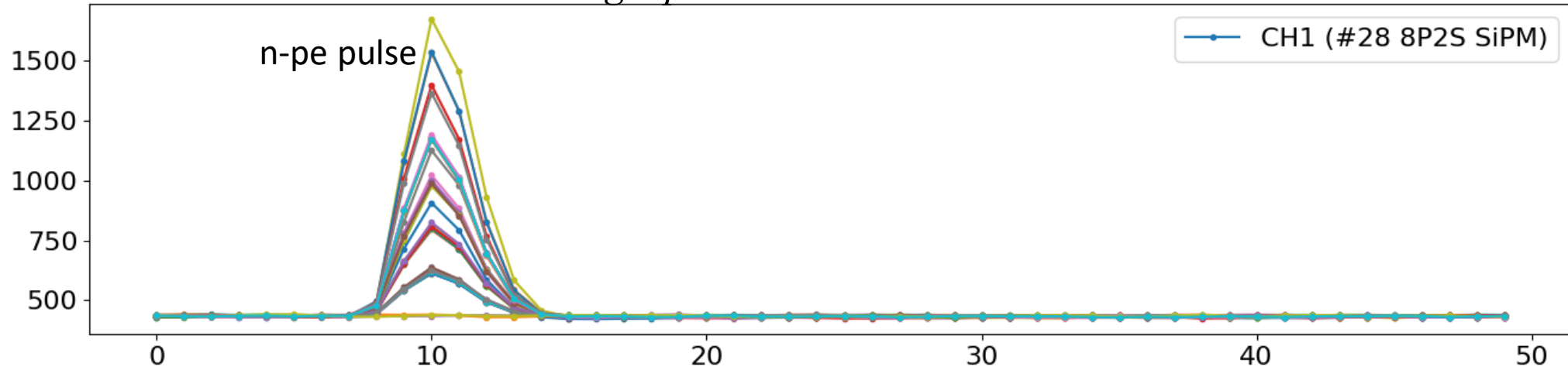
*Photon flash trigger (100 Hz) and the 2 MHz ADC can dither by  $0.5 \mu\text{s}$  (1 time-tick)*

*single photoelectrons*



# time coincidence detection: 10 MHz reference clock lock ON

*single photoelectrons*



Time tick [ $0.5\mu\text{s}/\text{tick}$ ] total of  $500\mu\text{s}$

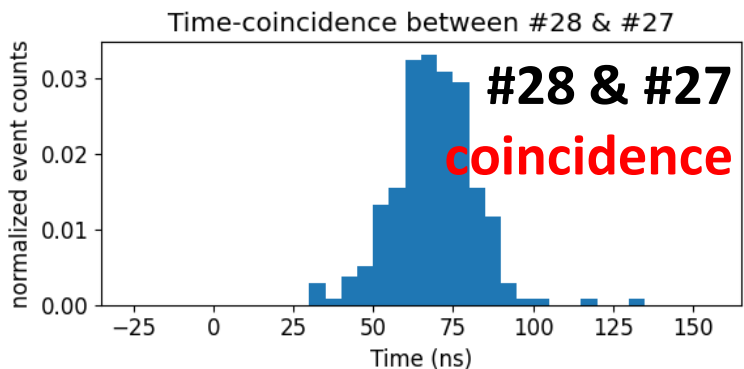
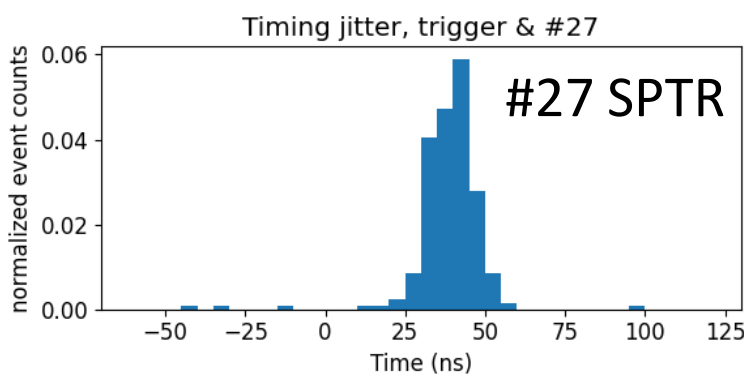
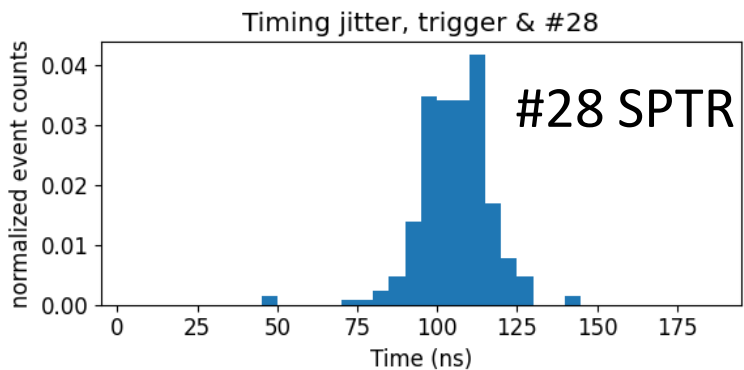
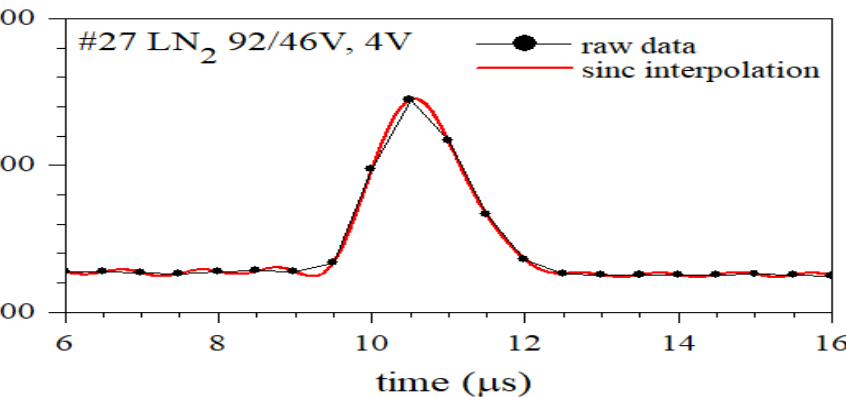
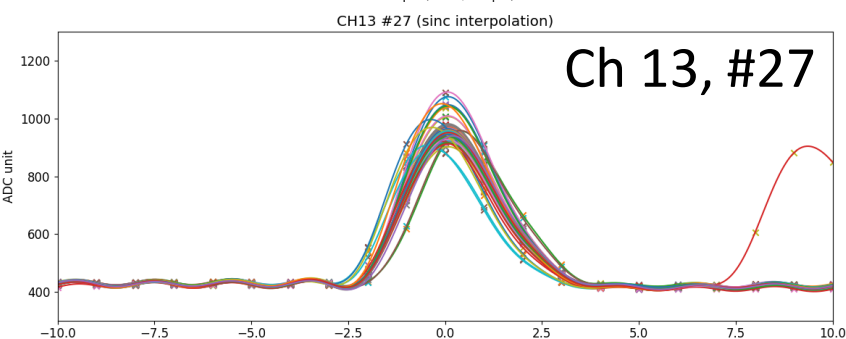
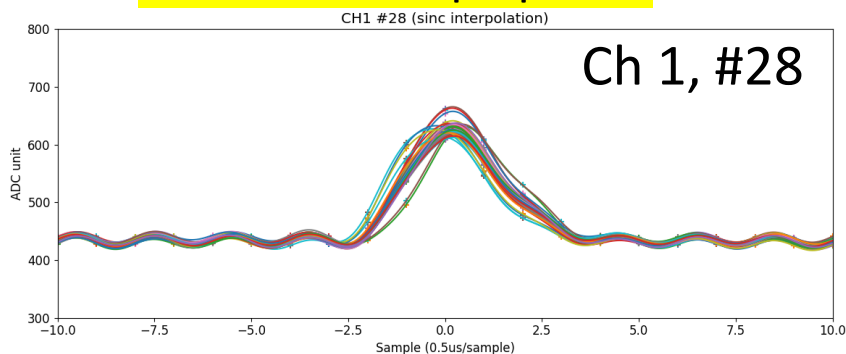
↑  
trigger

*Note: #28 and #27 have different charge gain*

# Single-Photoelectron Timing and **Coincidence** Resolution

1-pe time jitter histogram, 45 sec data

Select ONLY 1-pe pulses



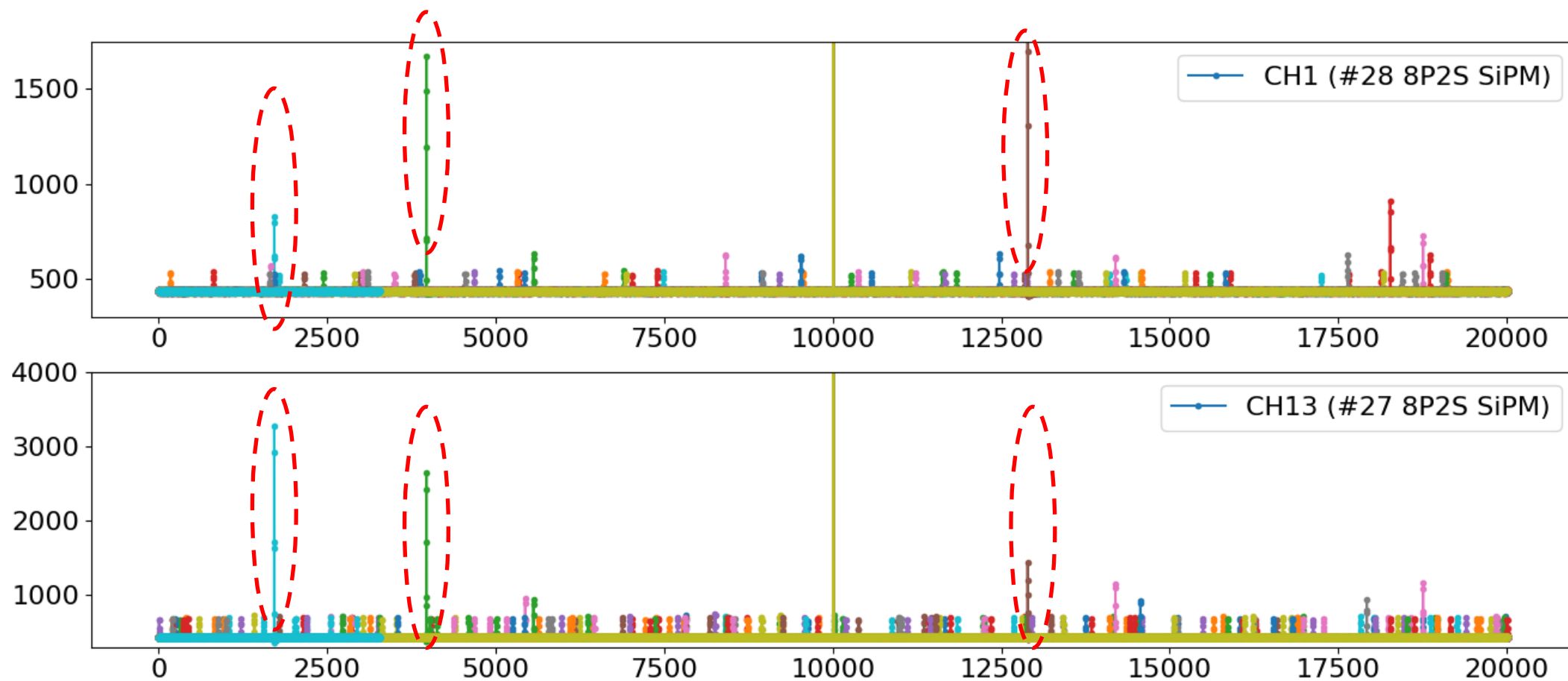
Photon flash 100 Hz  
ADC sampling rate 2 MHz

LN <sub>2</sub> 4V	Average rate (Hz)	SPTR (ns)
#28	96	9.94
#27	250.6	6.57
<b>Coinc.</b>	67.3	<b>~11 ns</b>

coincidence  
window = 0.5 μs

*Time coincidence detection  
of Dark Pulses ...*

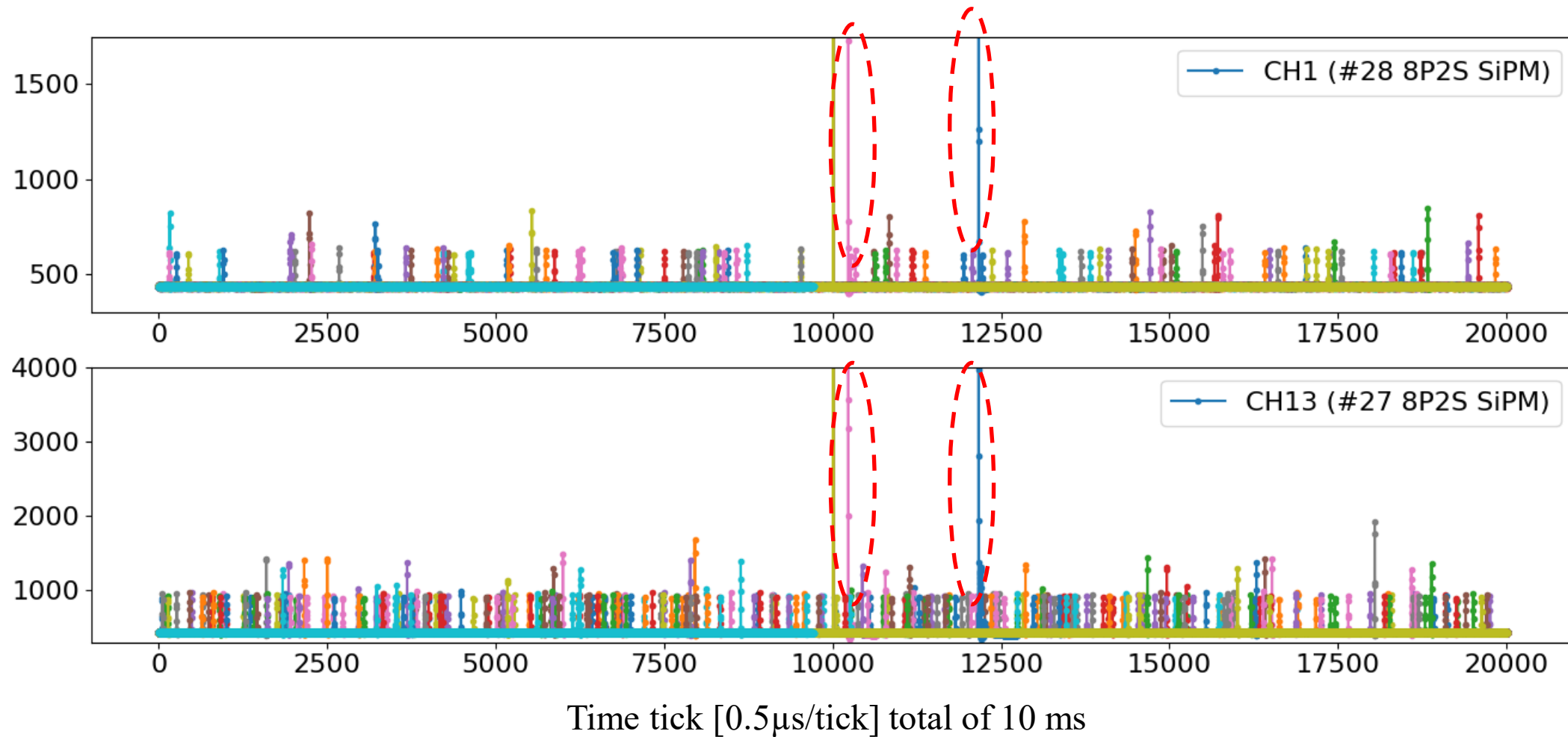
# unexpected time-correlated DARK events (2.2V, 10 ms cumulative)



Time tick [ $0.5\mu\text{s}/\text{tick}$ ] total of 10 ms

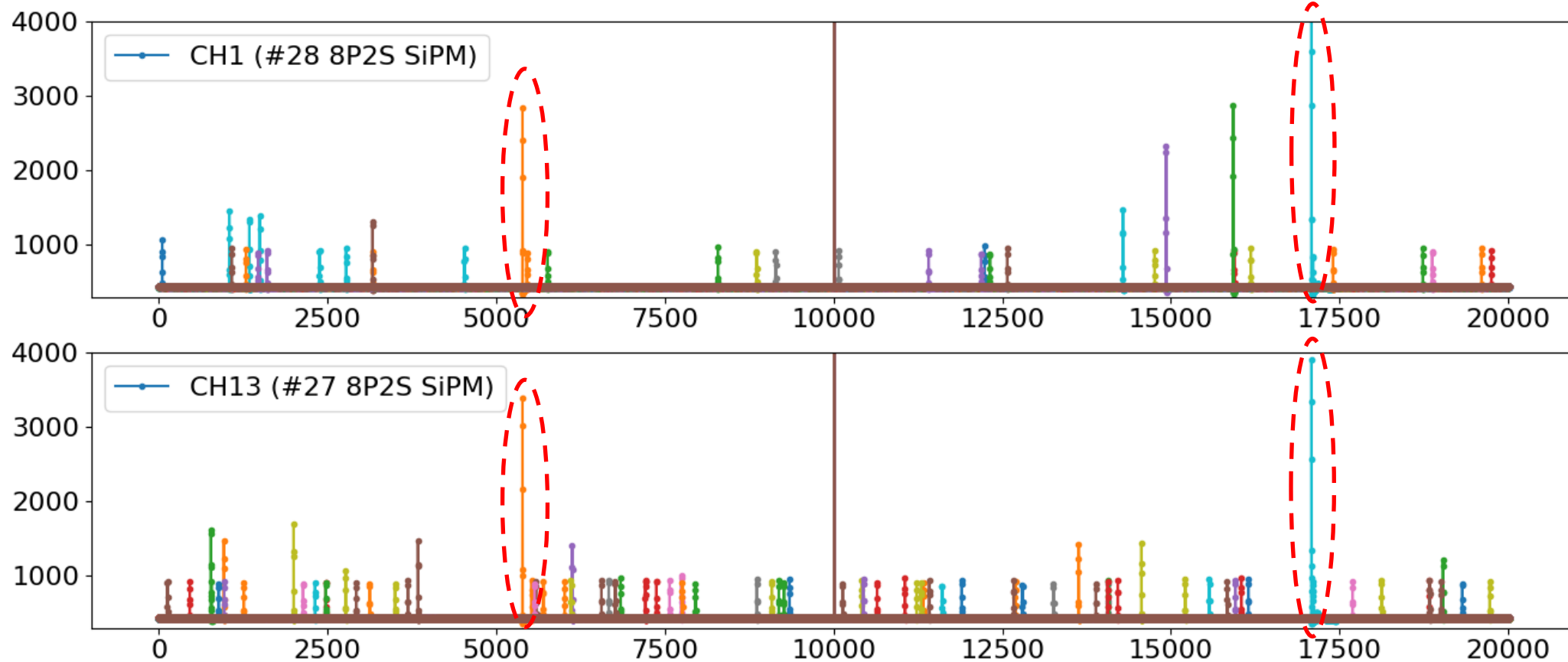
time-coincident events  $\sim 1\%$  of total DCR

# unexpected time-correlated DARK events (4.2V, 10 ms cumulative)



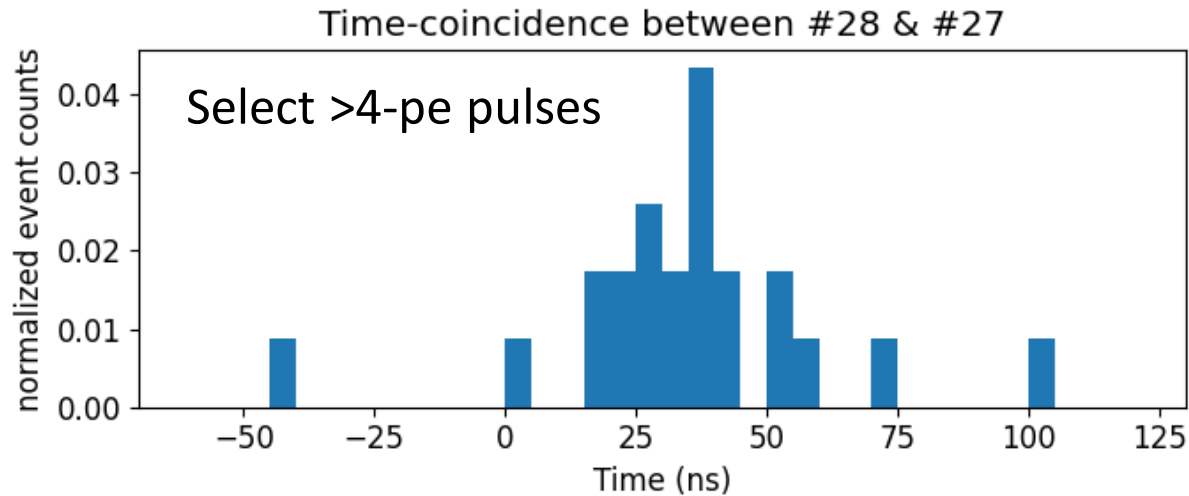


# unexpected time-correlated DARK events (4.2V, 10 ms cumulative)



Time tick [0.5μs/tick] total of 10 ms

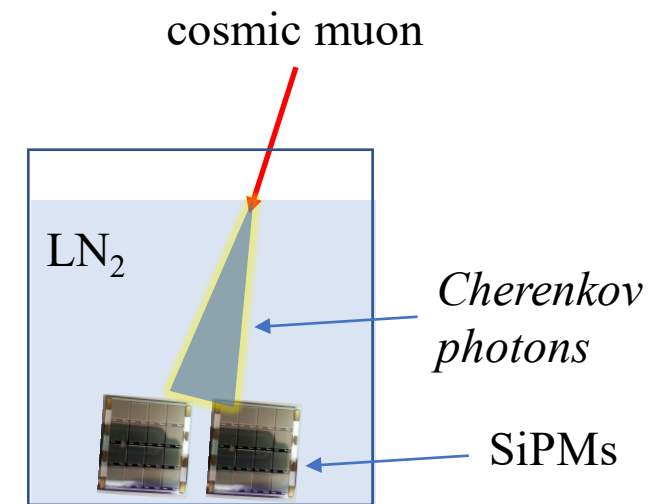
# Hypothesis of time-correlated DARK events: cosmic muon triggered



LN <sub>2</sub> 4V	Muon trigger Rate (Hz)	Coinc time (ns) rms
#28	1.3	
#27	1.8	
Coinc.	0.3	<b>9.2 ns</b>

Accidental coincidence =  $2 R_{28} R_{27} (0.5 \text{ us}) = 2.25 \times 10^{-6} \ll$  coincidence rate 0.28

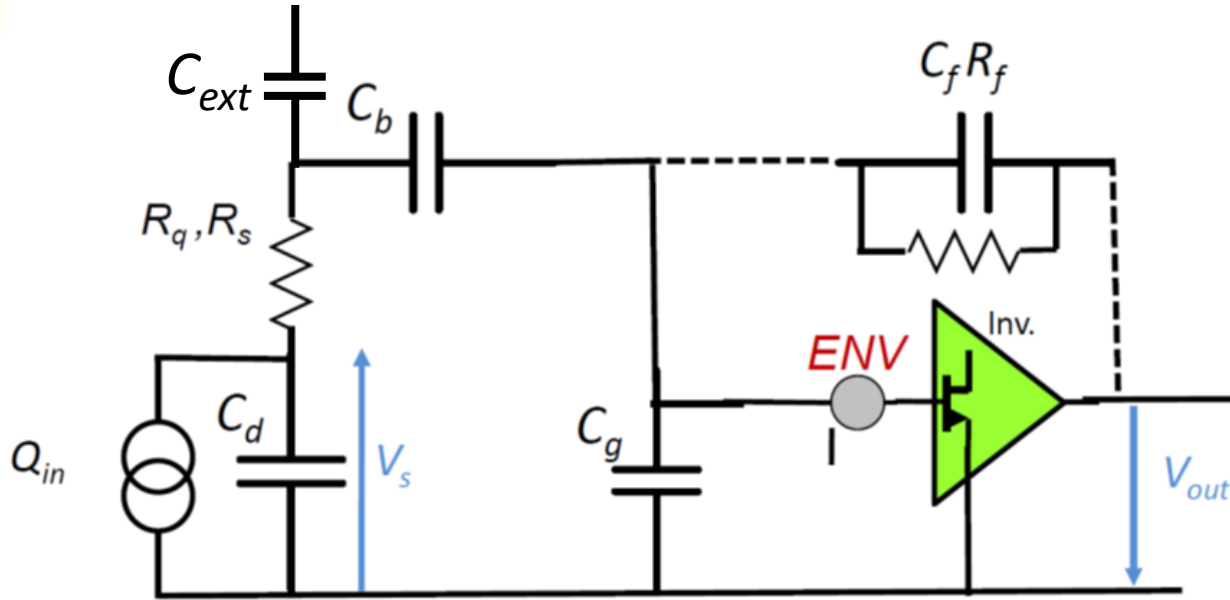
1. event rate in Dark  $\sim 1$  Hz,  $\sim 1\%$  of total DCR ( $\sim 100$ Hz)
2. We believe intense  $>n$ -photoelectron light pulses are triggered by cosmic muon
3. At sea-level, cosmic-muon event rate  $\sim 1$  muon/cm<sup>2</sup>/minute
4. SiPMs tile quartz window, quartz scatter plate, and  $\sim 200$  cm<sup>3</sup> LN<sub>2</sub> could see  $\sim$ Hz of Cherenkov light.



# *SiPM terminal capacitance measurements*

# Terminal capacitance ( $C_d$ ) measurement & charge calibration in LArASIC

step  $V_{ext}$



minitile in LArASIC Cd calculation

gain (mV/fC)	4.7
C b (pF)	500
C int (pF)	0.183
C ext (pF)	1
V int (volt)	0.35
V ext (volt)	0.5
ADC int (ADC)	700

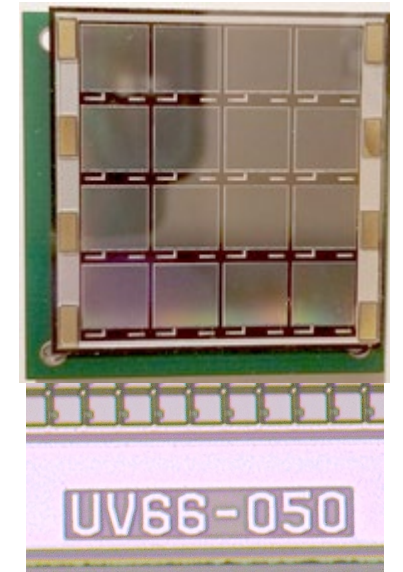
ADC ext (ADC) to be measured

$$\frac{C_d}{C_b} = \left[ \frac{V_{ext}}{V_{int}} \right] \left[ \frac{C_{ext}}{C_{int}} \right] \left[ \frac{ADC_{int}}{ADC_{ext}} \right] - 1$$

**HPK 5.76 cm<sup>2</sup> SiPM tile 8P2S**

**$C_{terminal}$  (room) ~5.8 nF**

**$C_{terminal}$  (LN<sub>2</sub>) 1.9 nF**



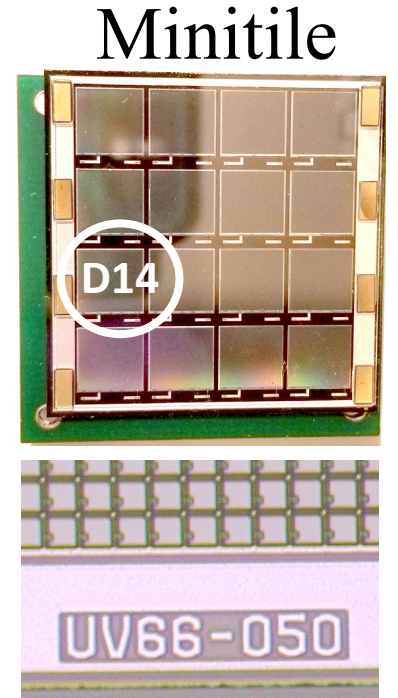
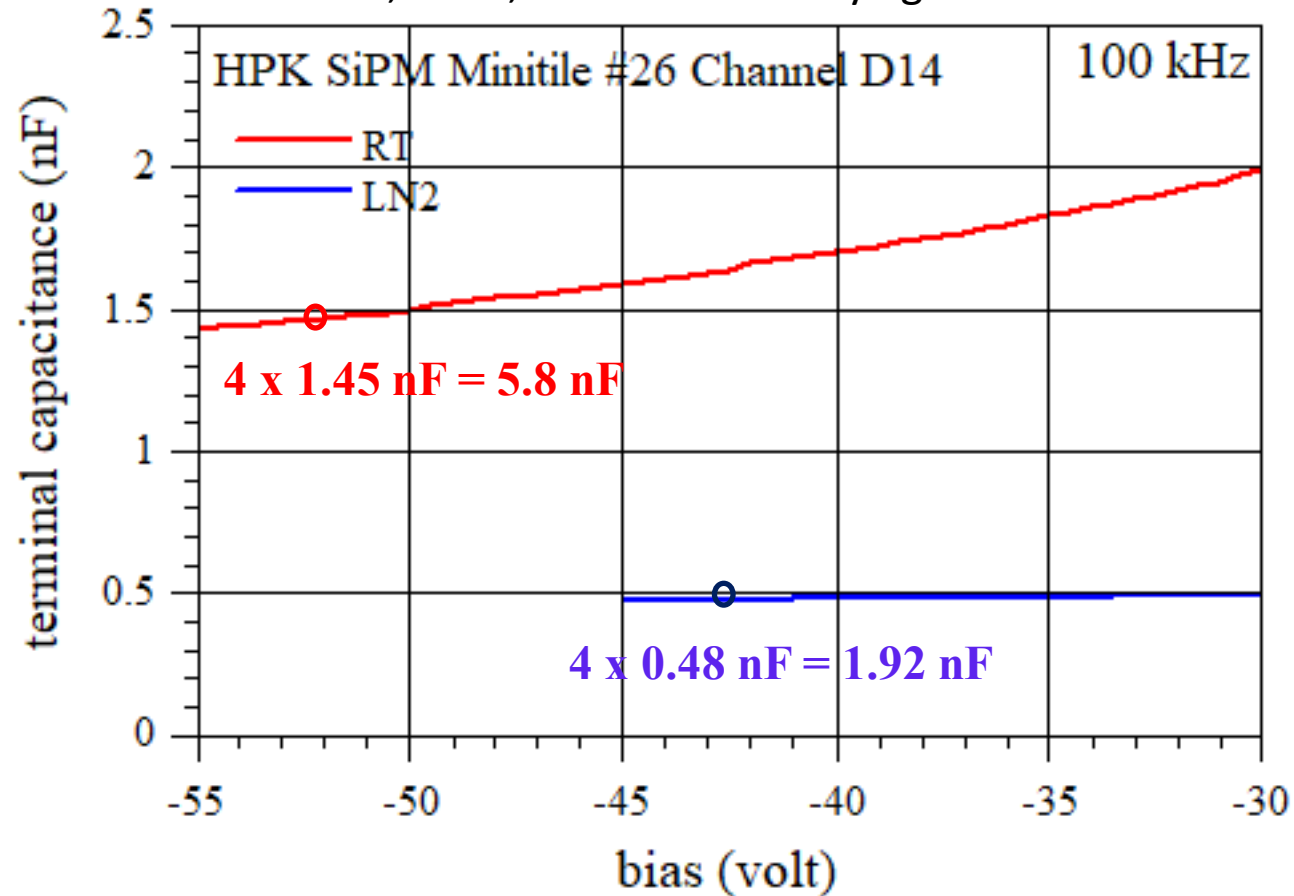
# Terminal capacitance ( $C_d$ ) measurement using LCR bridge

HPK Minitile #26, single 6x6 mm<sup>2</sup> SiPM #D14

KeySight B1500A  
semiconductor device analyzer



Feb 5, 2021, measured on KeySight B1500A

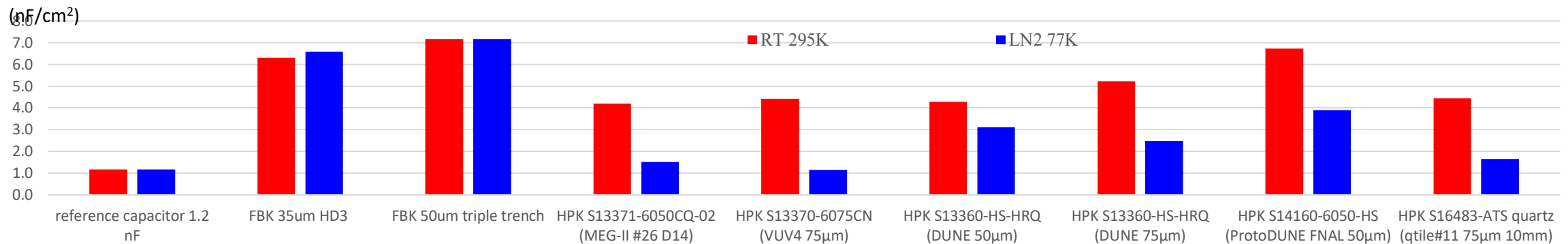


**HPK Minitile SiPM terminal capacitance drop by a factor of ~3 from RT to LN<sub>2</sub> (but  $\mu$ Cell capacitance remain approx. the same)**

# Terminal capacitance of various SiPMs: RT and LN<sub>2</sub>

Terminal capacitance measured by a Cremat bridge	RT		LN2			
	nF (nF/cm <sup>2</sup> )		nF (nF/cm <sup>2</sup> )		gain/OV x 10 <sup>6</sup>	cap. (nF/cm <sup>2</sup> )
reference capacitor 1.2 nF	1.17	1.170	1.17	1.170		
FBK 35um HD3	2.269	6.302	2.370	6.583	0.57	6.47
FBK 50um triple trench	2.578	7.161	2.58	7.167	1.43	7.11
HPK S13371-6050CQ-02 (MEG-II #26 D14)	1.510	4.194	0.540	1.500	0.68	4.22
HPK S13370-6075CN (VUV4 75μm)	1.590	4.417	0.410	1.139		
HPK S13360-HS-HRQ (DUNE 50μm)	1.540	4.278	1.120	3.111	0.666	4.28
HPK S13360-HS-HRQ (DUNE 75μm)	1.880	5.222	0.890	2.472	1.484	4.19
HPK S14160-6050-HS (ProtoDUNE FNAL 50μm)	2.420	6.722	1.400	3.889	1.104	5.50
HPK S16483-ATS quartz (qtile#11 75μm 10mm)	4.430	4.430	1.660	1.660	1.48	4.18

Terminal Capacitance of SiPM at ~0V over-voltage measurement: Cremat CR111 + 1 μs shaper 0.47 nF decoupling cap.



- HPK SiPM terminal capacitance drops significantly from RT to LN<sub>2</sub> → higher S/N ratio
- μCell capacitance remain approx. the same → same charge gain
- Lowering of HPK's SiPM terminal capacitance in LN<sub>2</sub> have much benefit in photon readout: s/n improvement, lower total readout channels, lower overall detector cost ...

But we have yet to understand this phenomenon